

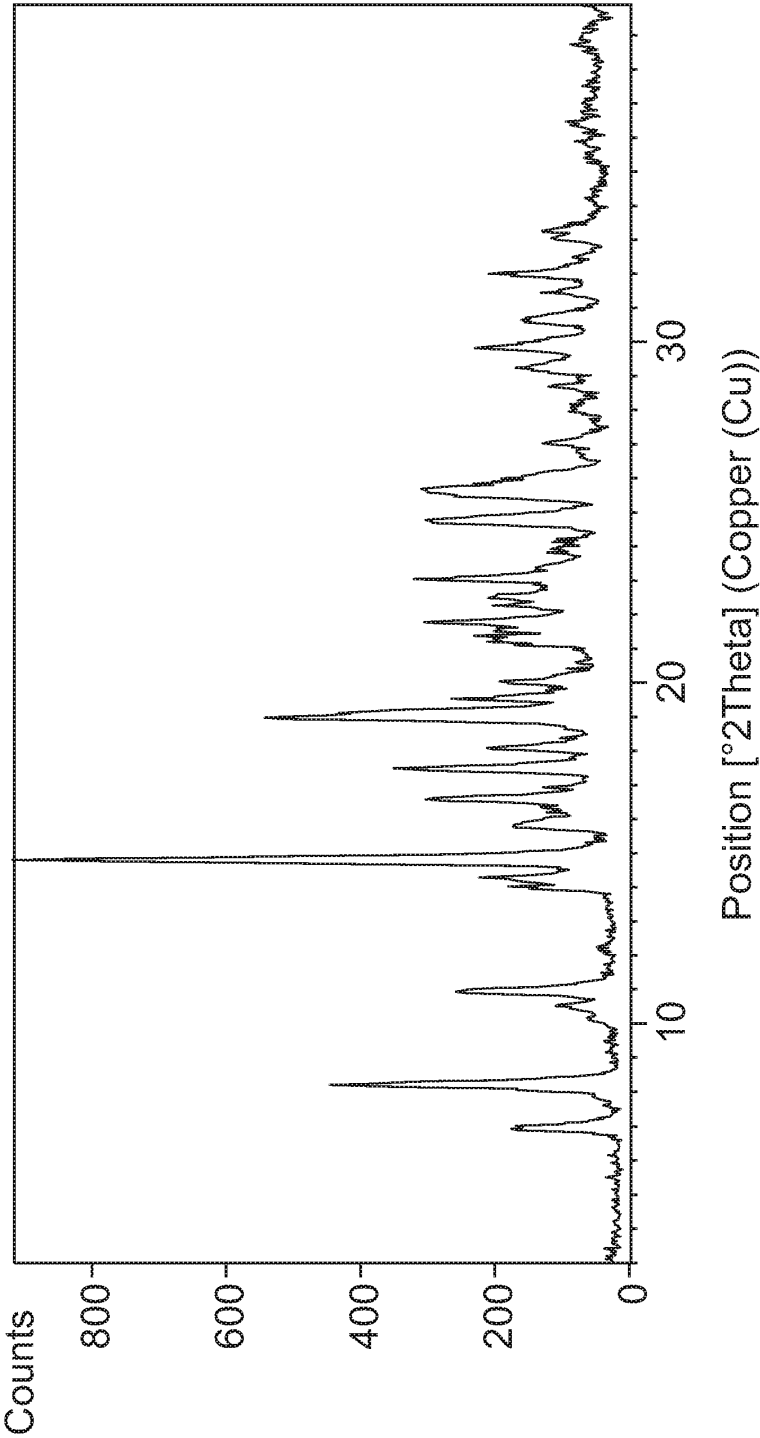


FIG. 1A

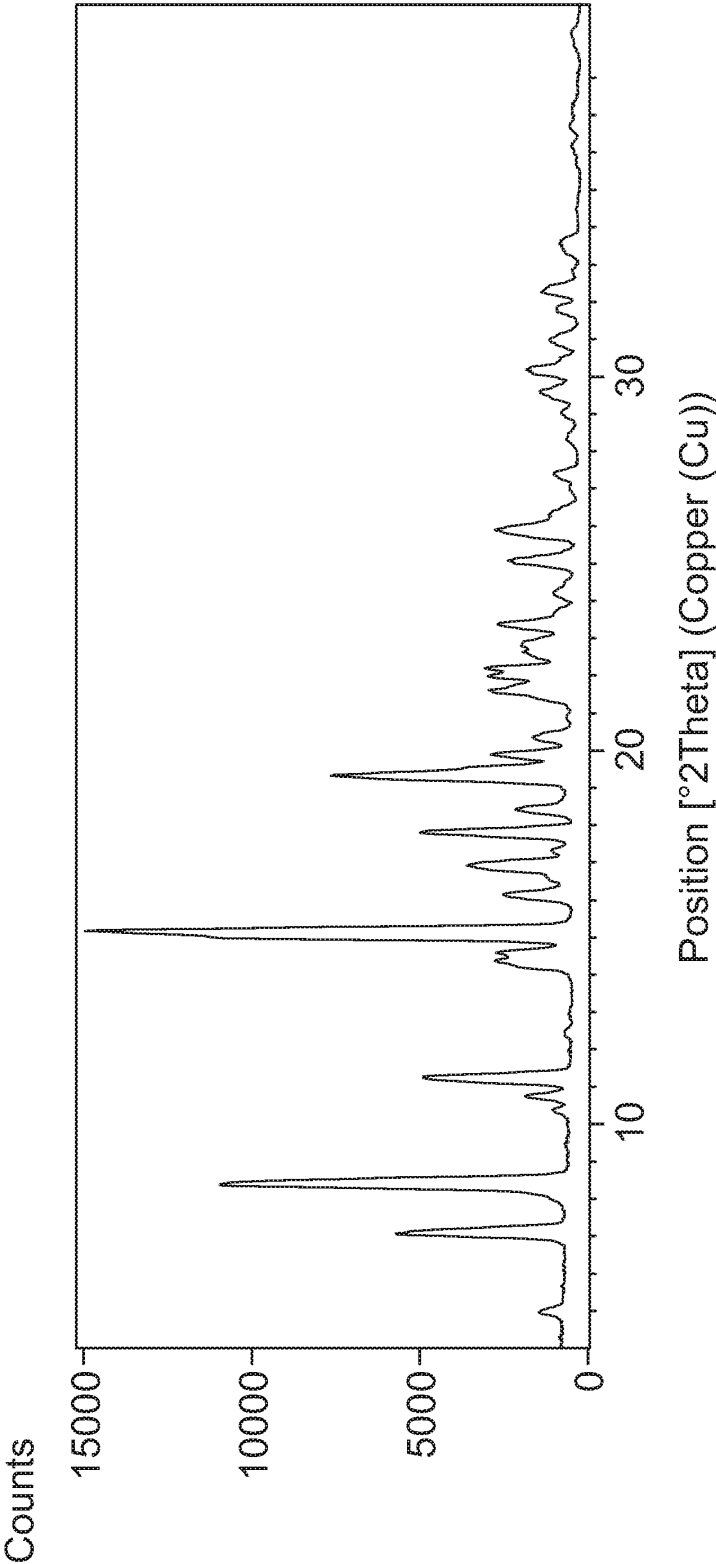


FIG. 1B

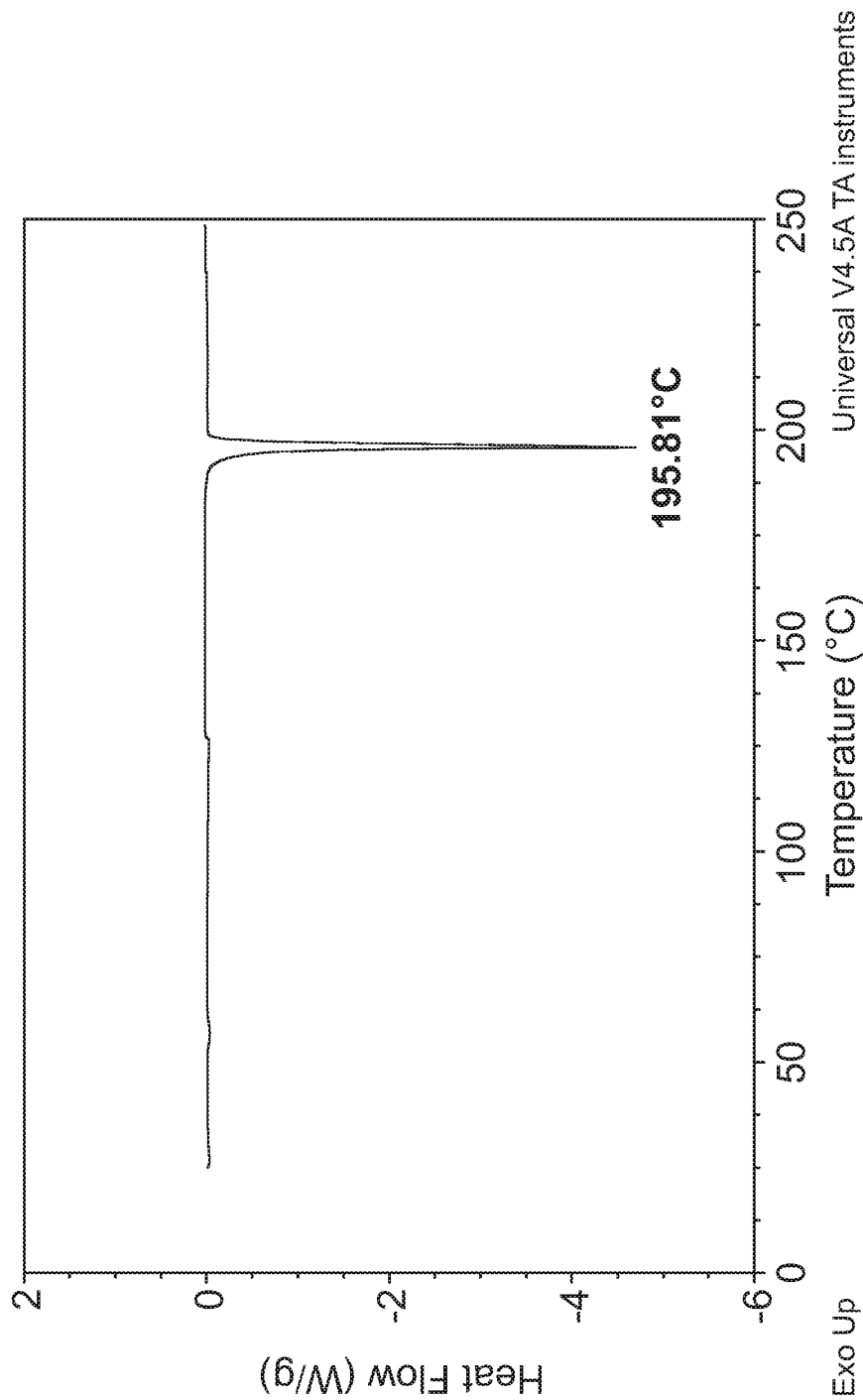


FIG. 2

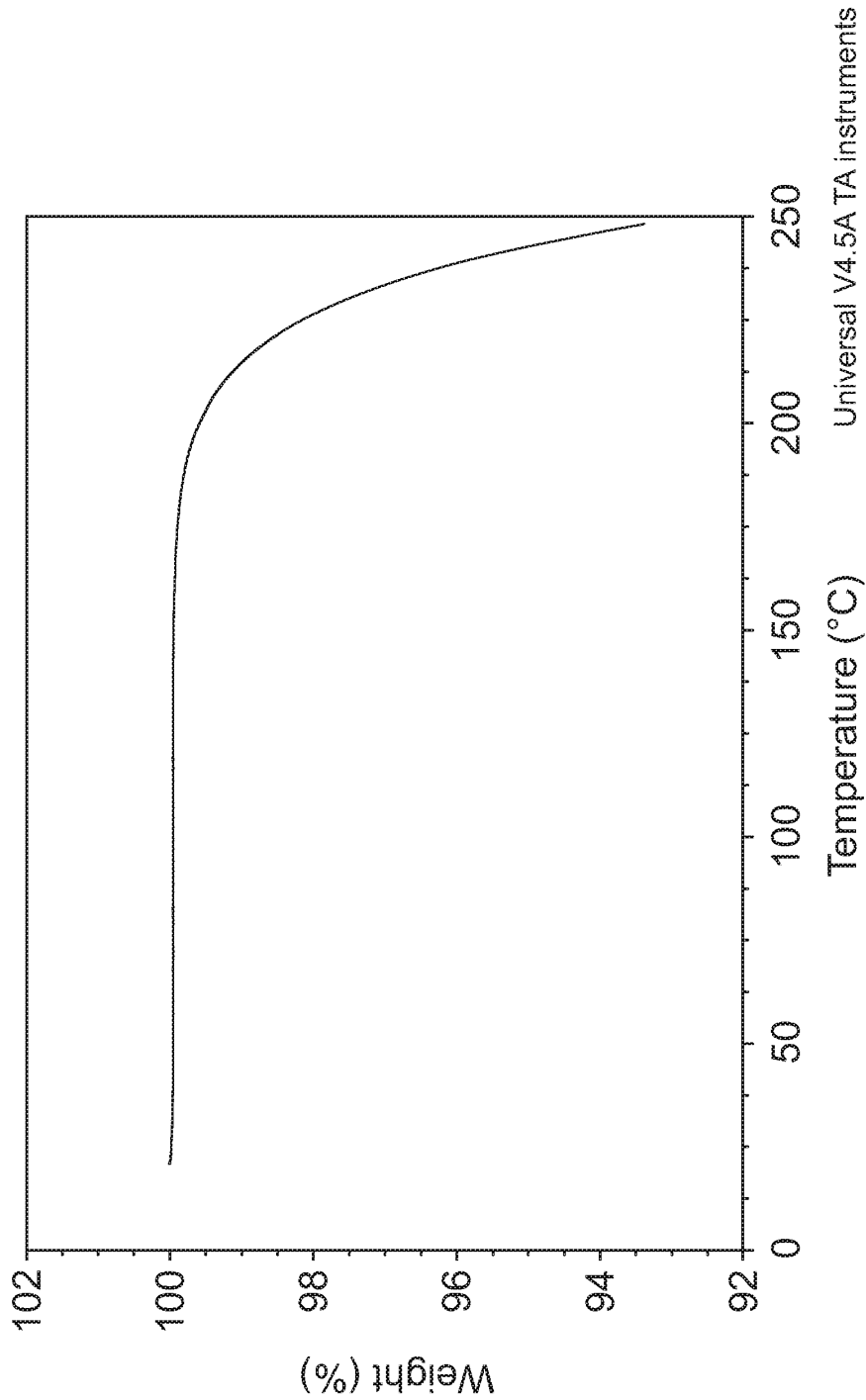
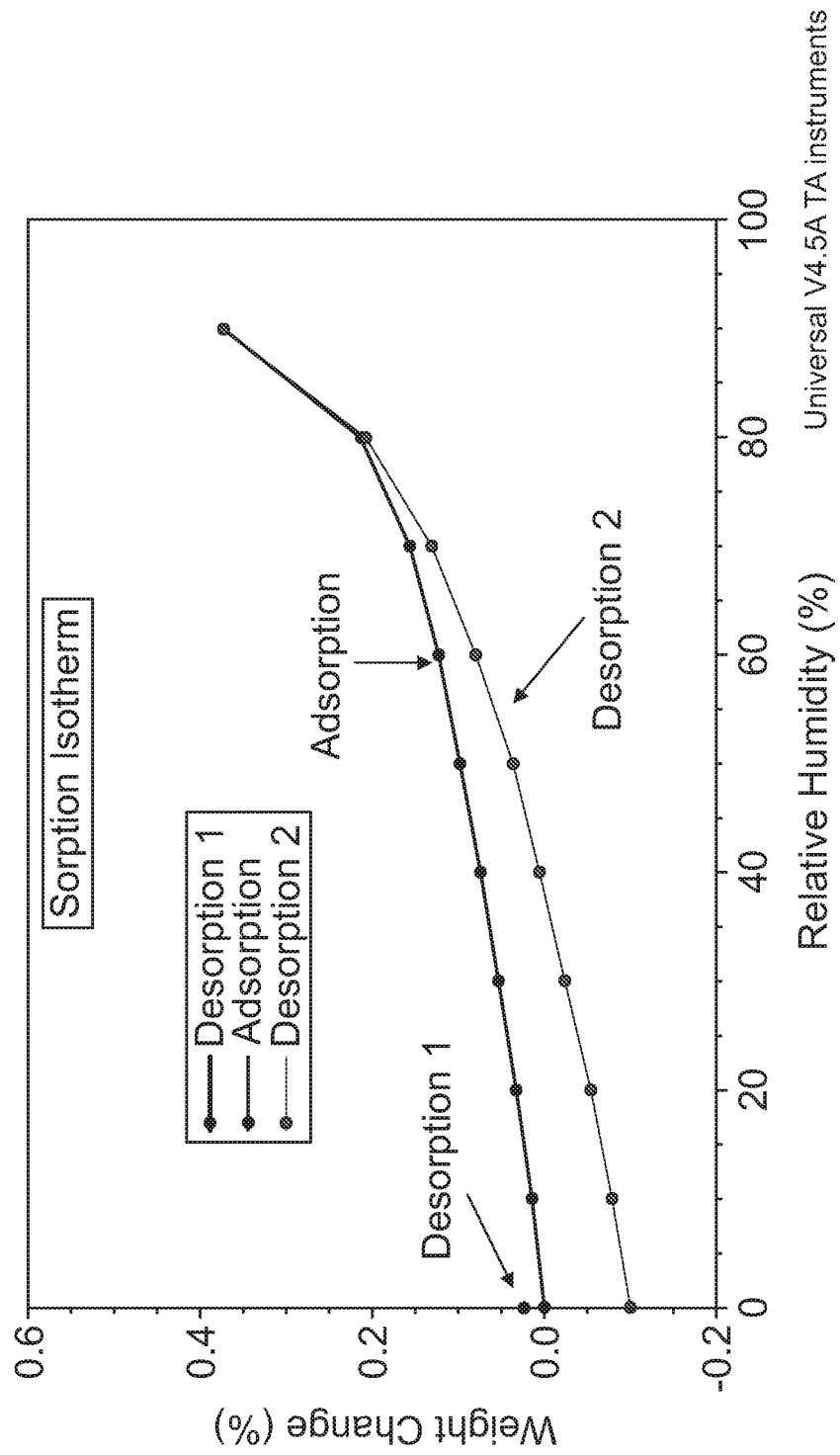


FIG. 3



Universal V4.5A TA instruments

FIG. 4

The figure is a line graph representing an X-ray diffraction (XRD) pattern. The vertical axis is labeled 'Counts' and ranges from 0 to 1000. The horizontal axis is labeled 'Position [°2Theta] (Copper (Cu))' and ranges from 0 to 35. The plot shows a series of sharp, well-defined diffraction peaks, particularly in the 10° to 25° range, which are characteristic of a crystalline phase. A prominent peak is observed at approximately 20° 2θ. Additionally, there is a broad, diffuse halo centered around 30° 2θ, suggesting the presence of an amorphous phase or very small crystallites. The overall pattern indicates a partially crystalline material.

Fig. 5A

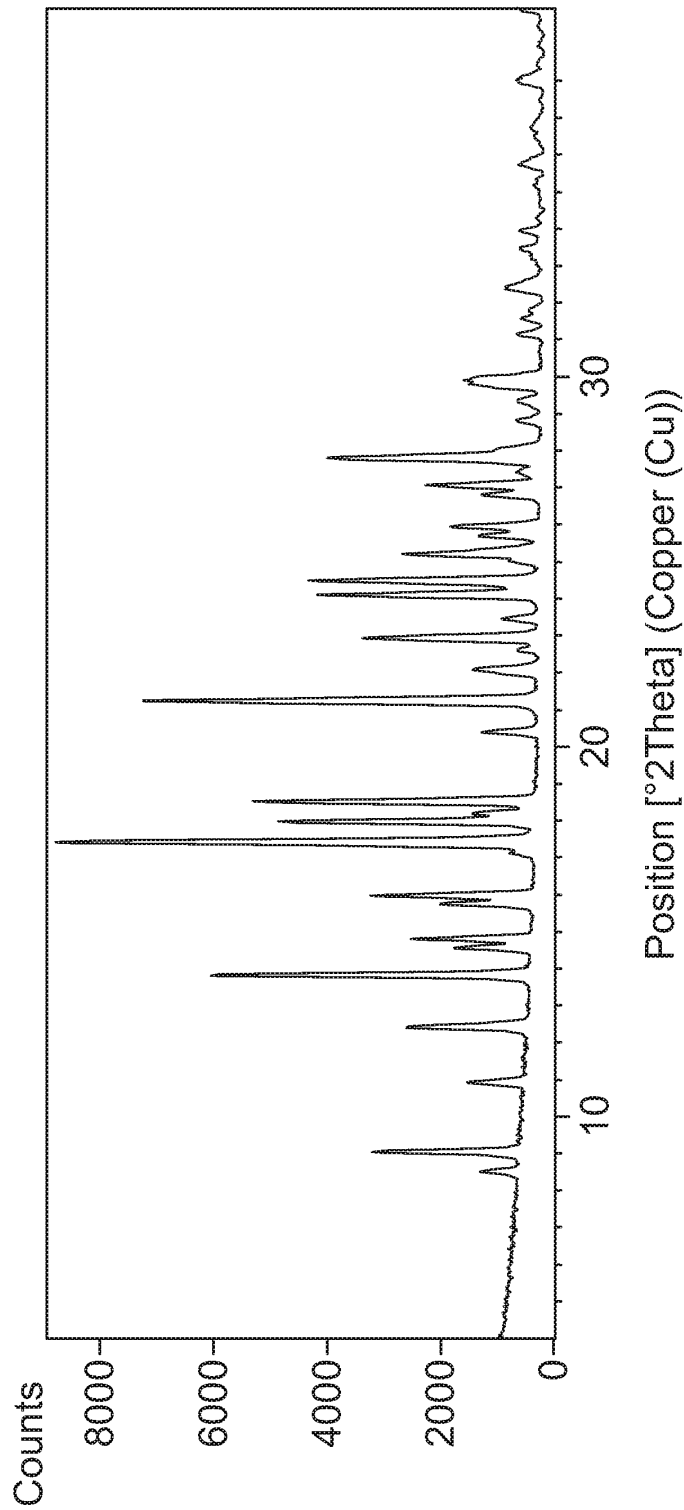


FIG. 5B

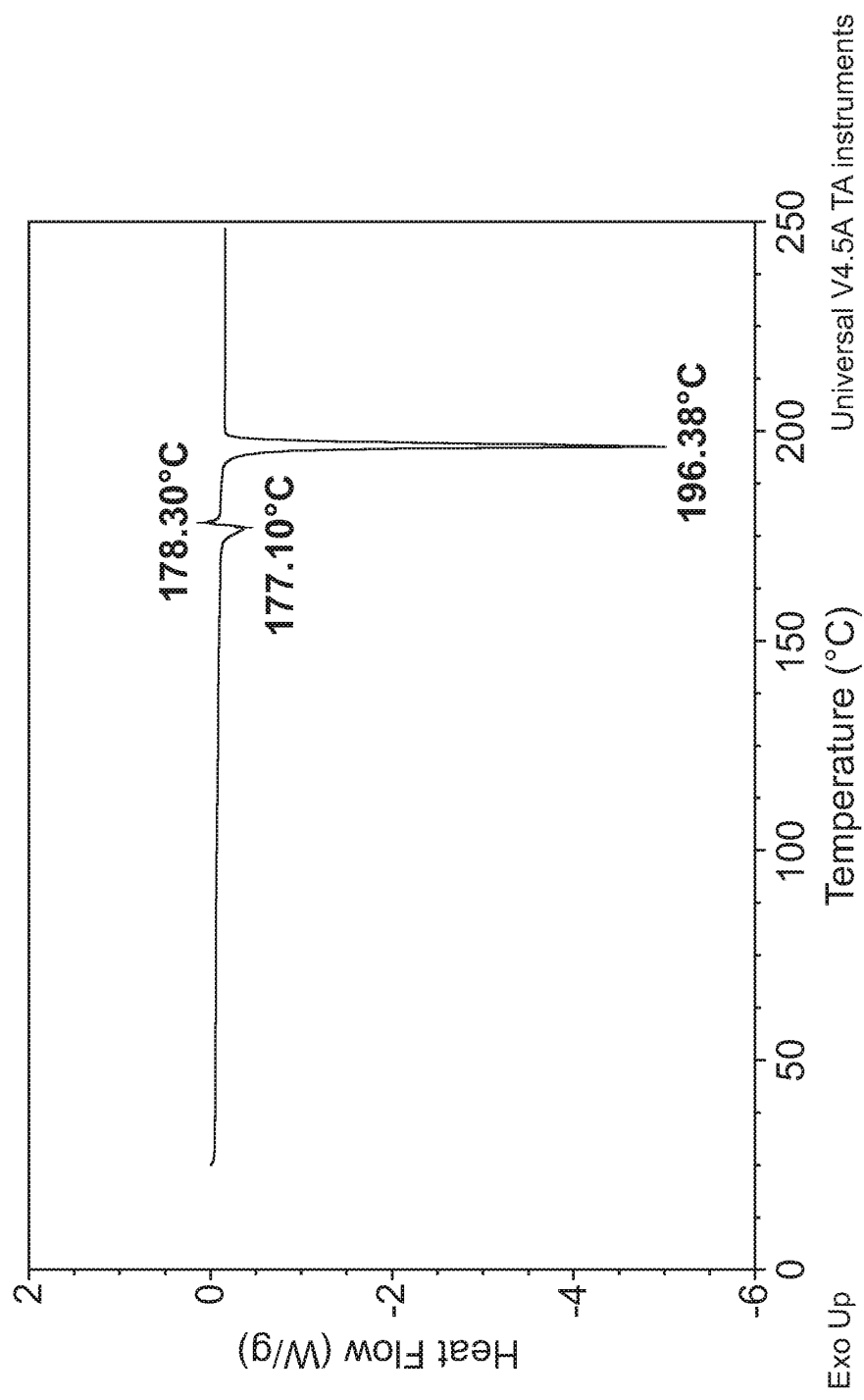


FIG. 6

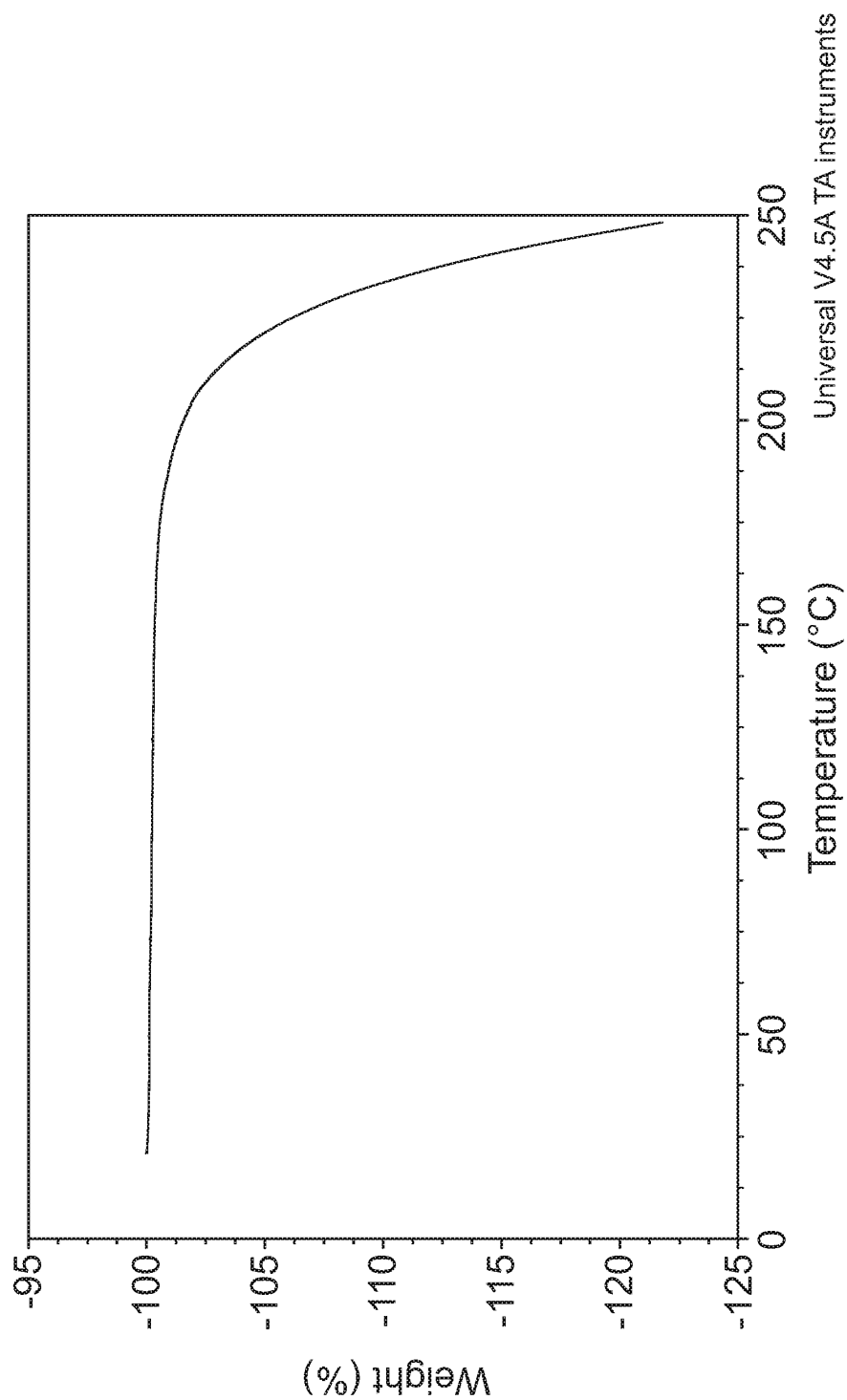


FIG. 7

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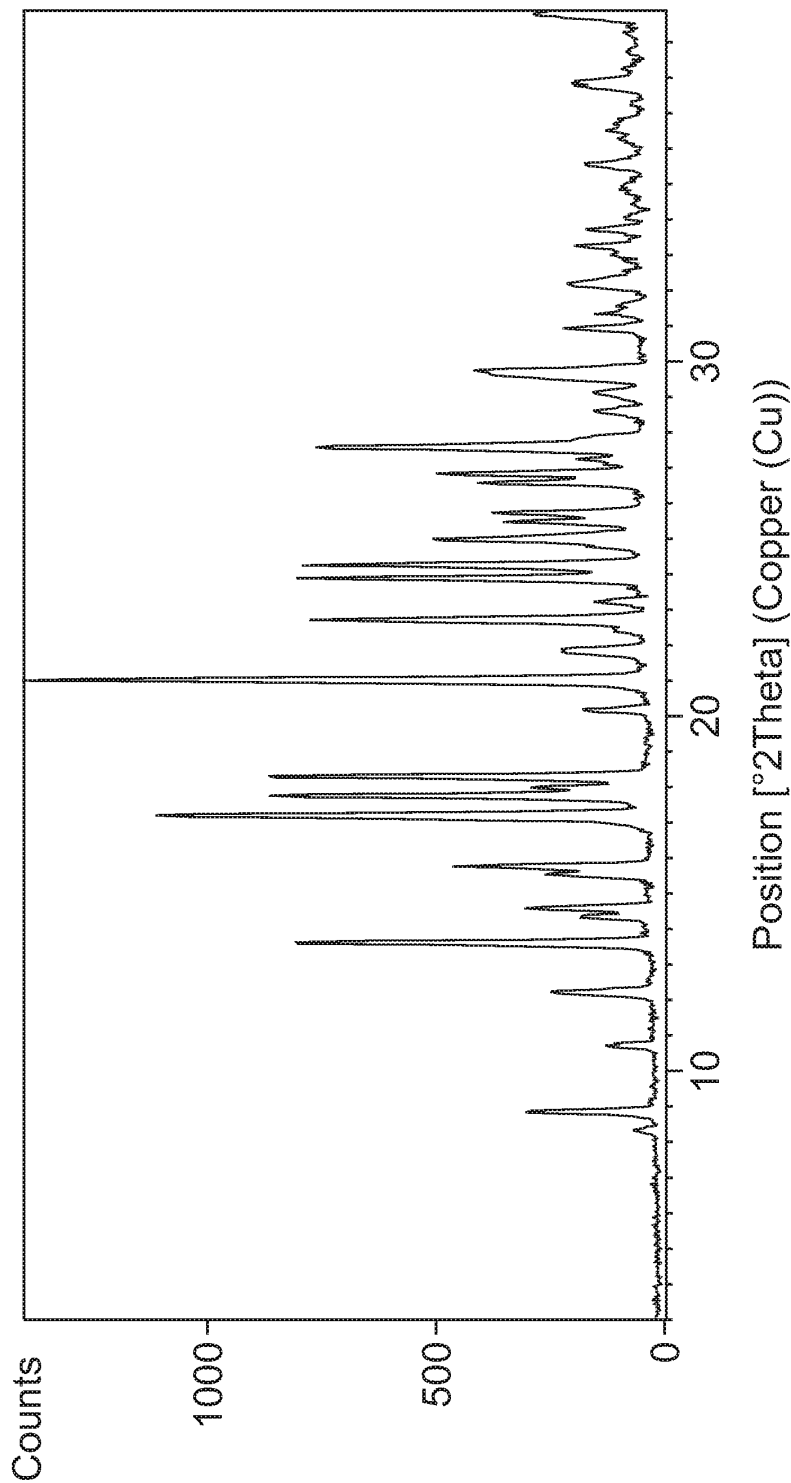


FIG. 8A

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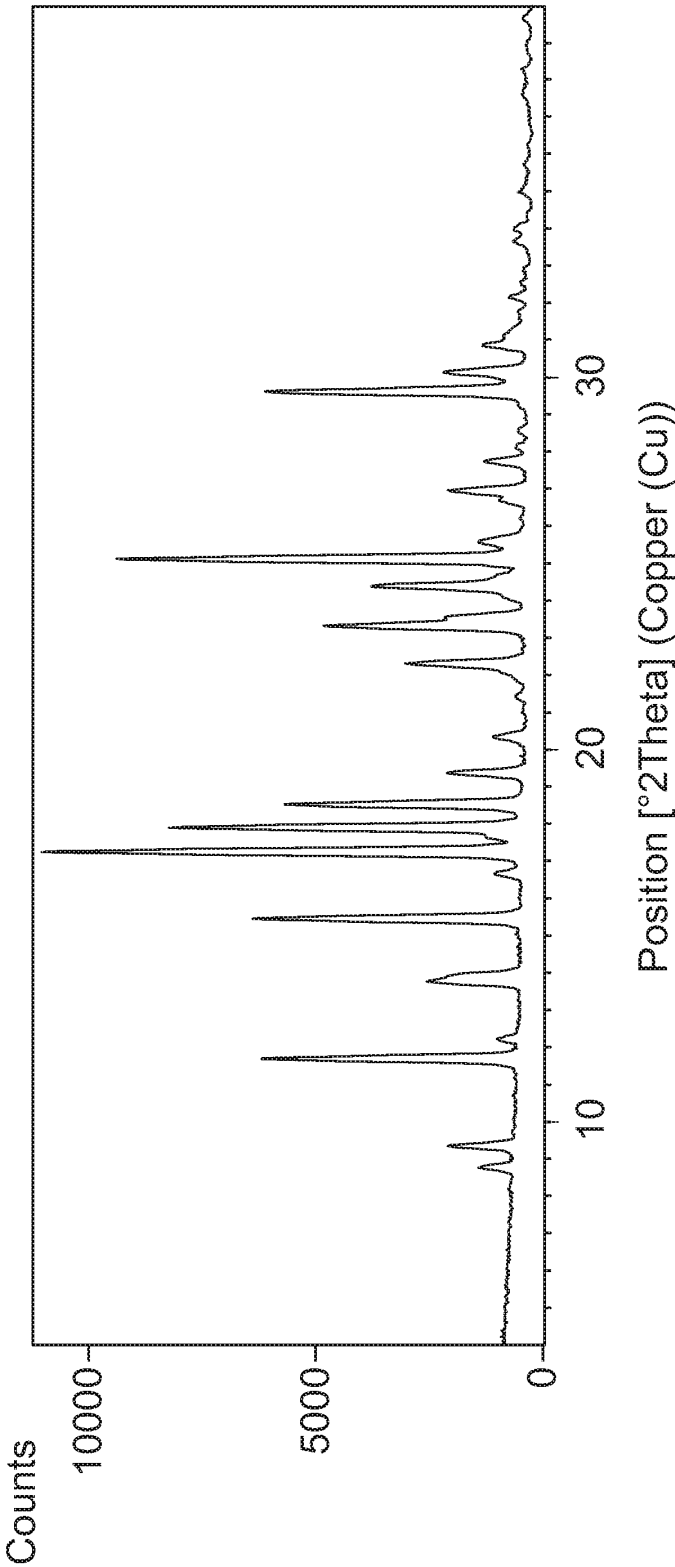


FIG. 8B

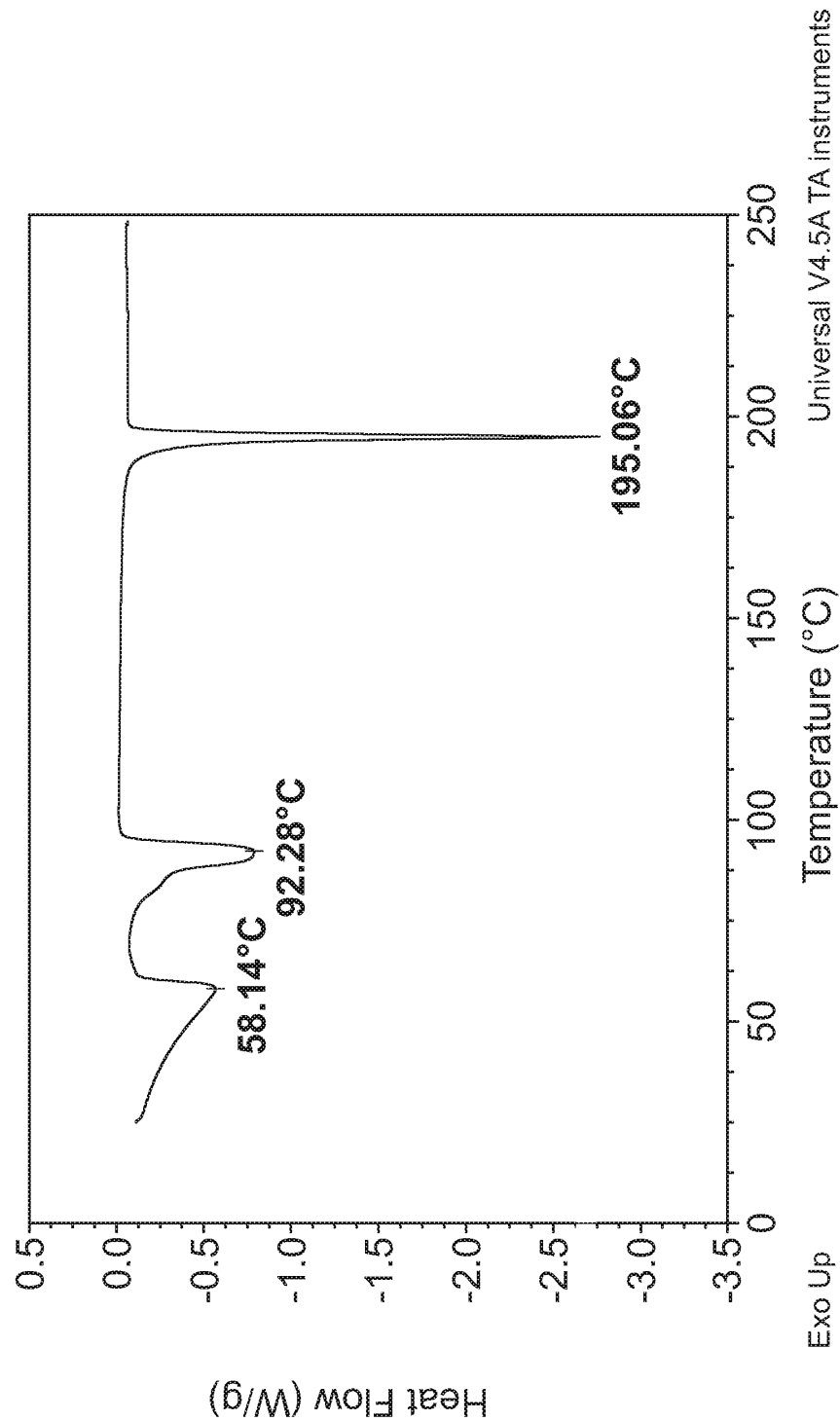


FIG. 9

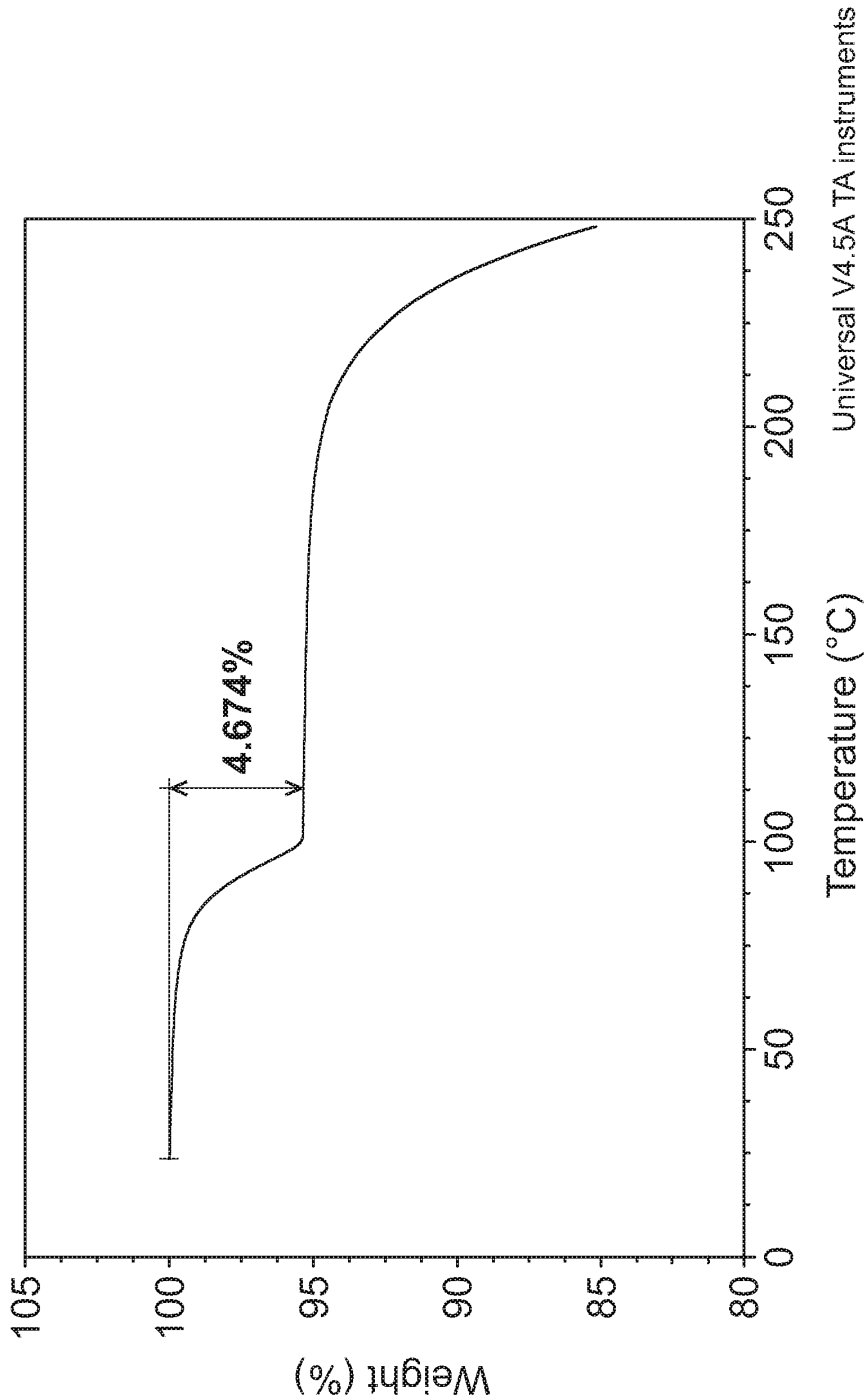


FIG. 10

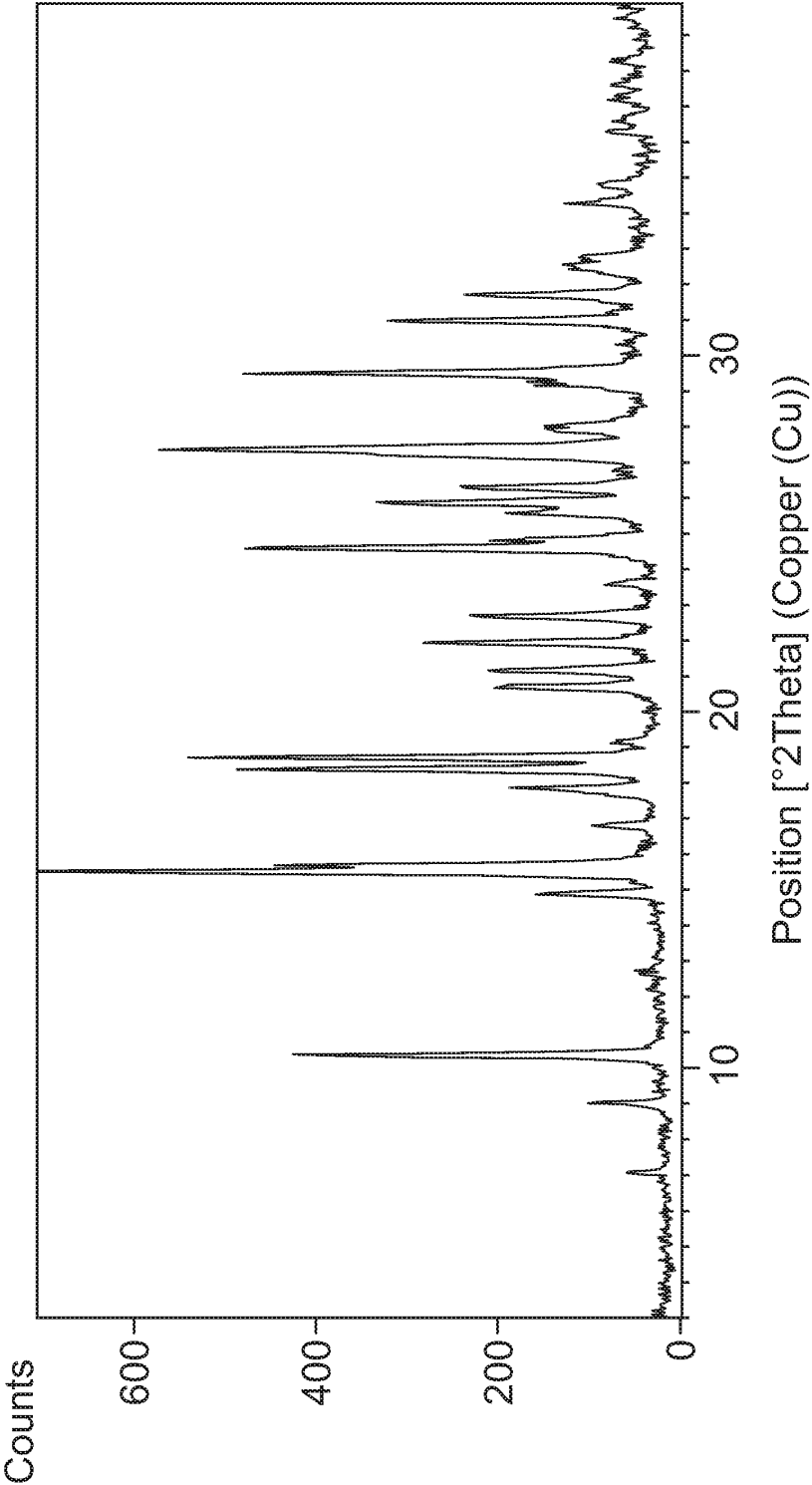


FIG. 11A

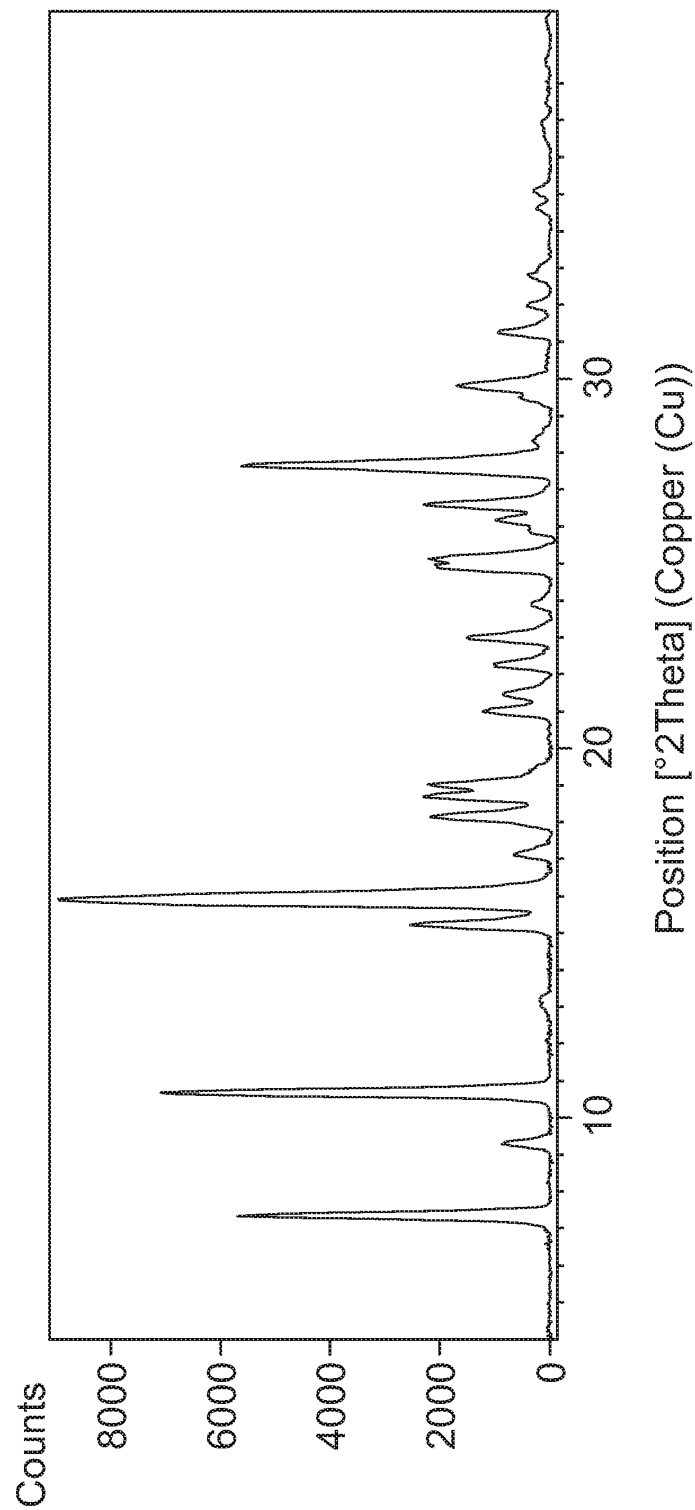


FIG. 11B

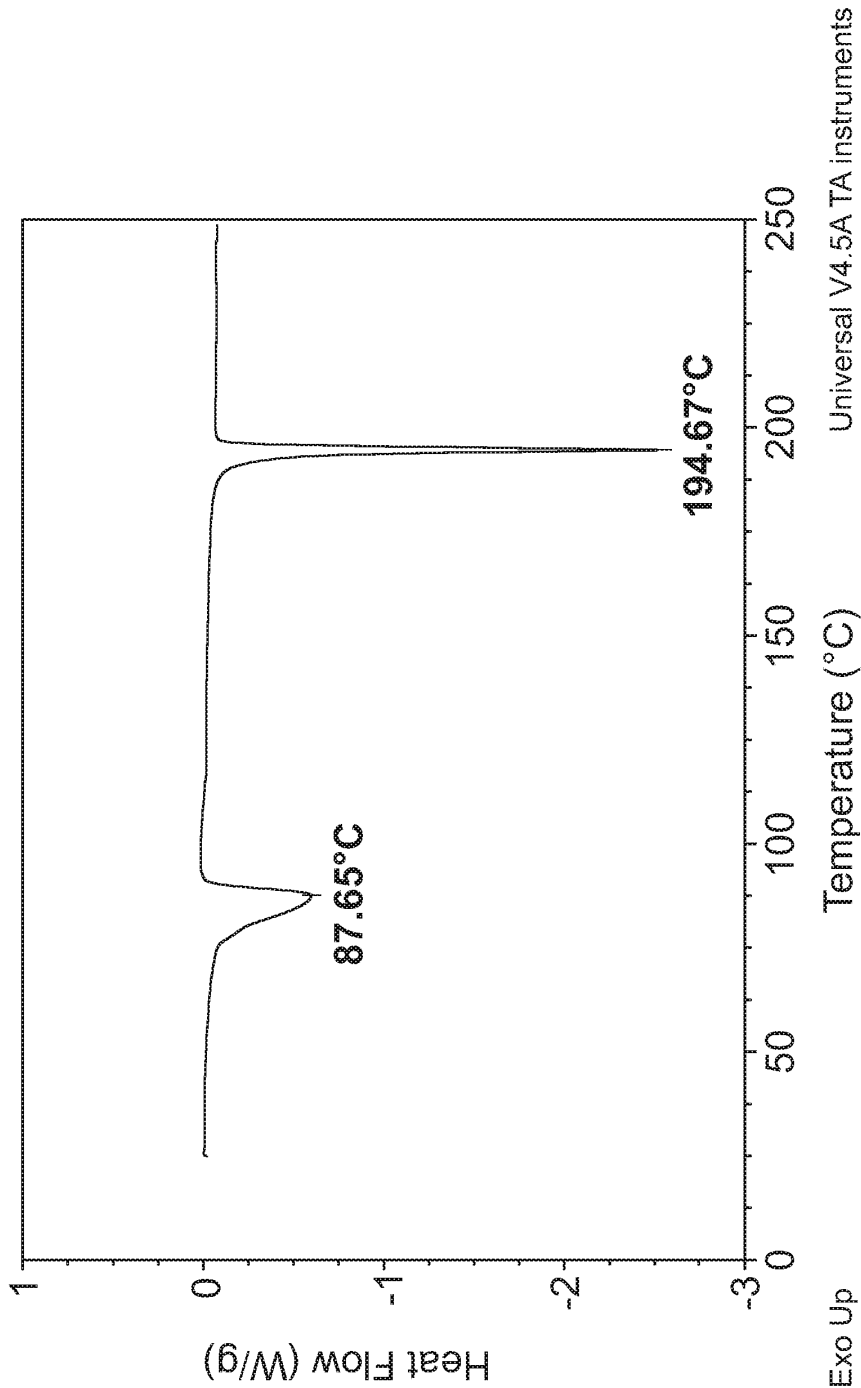


FIG. 12

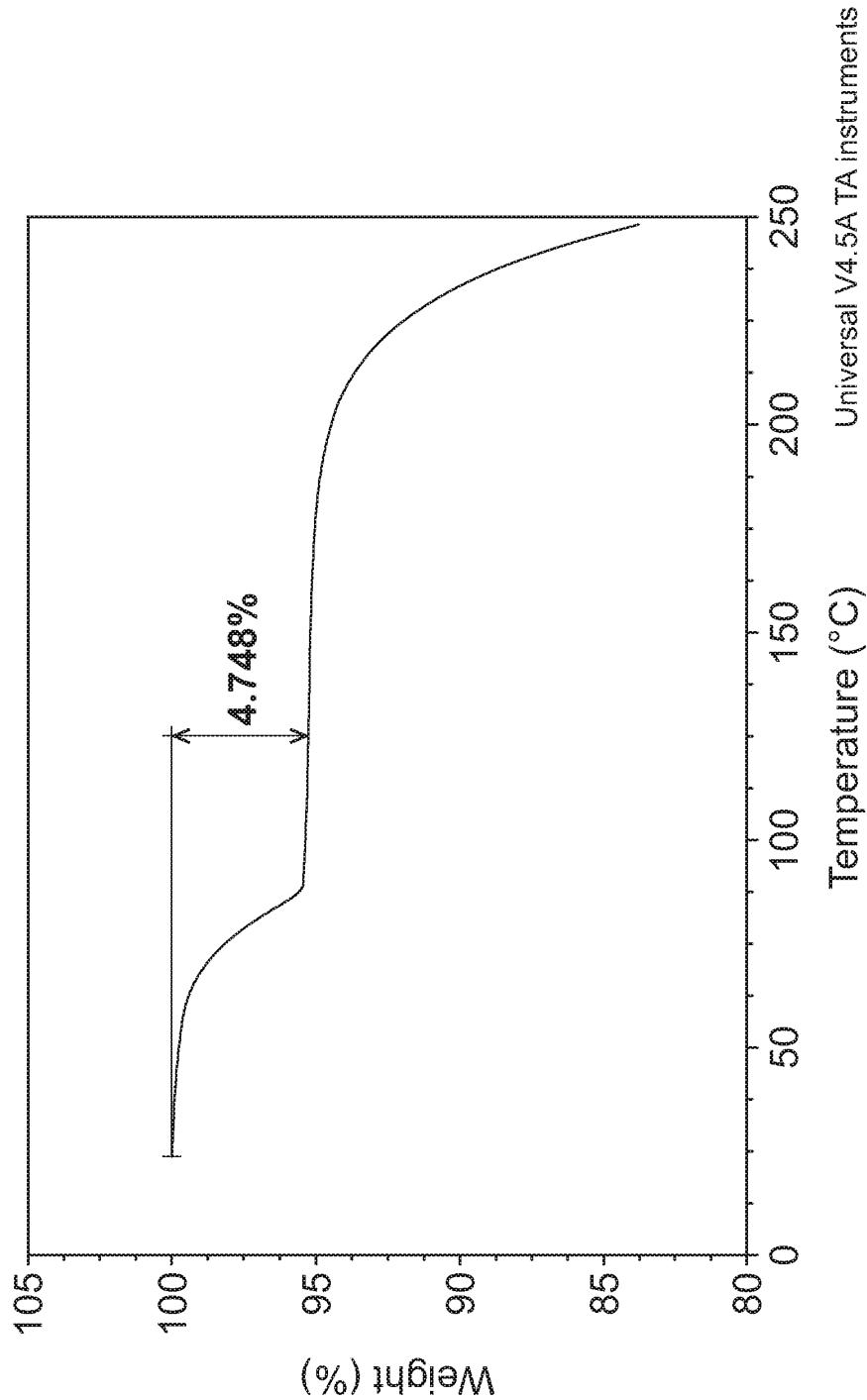


FIG. 13

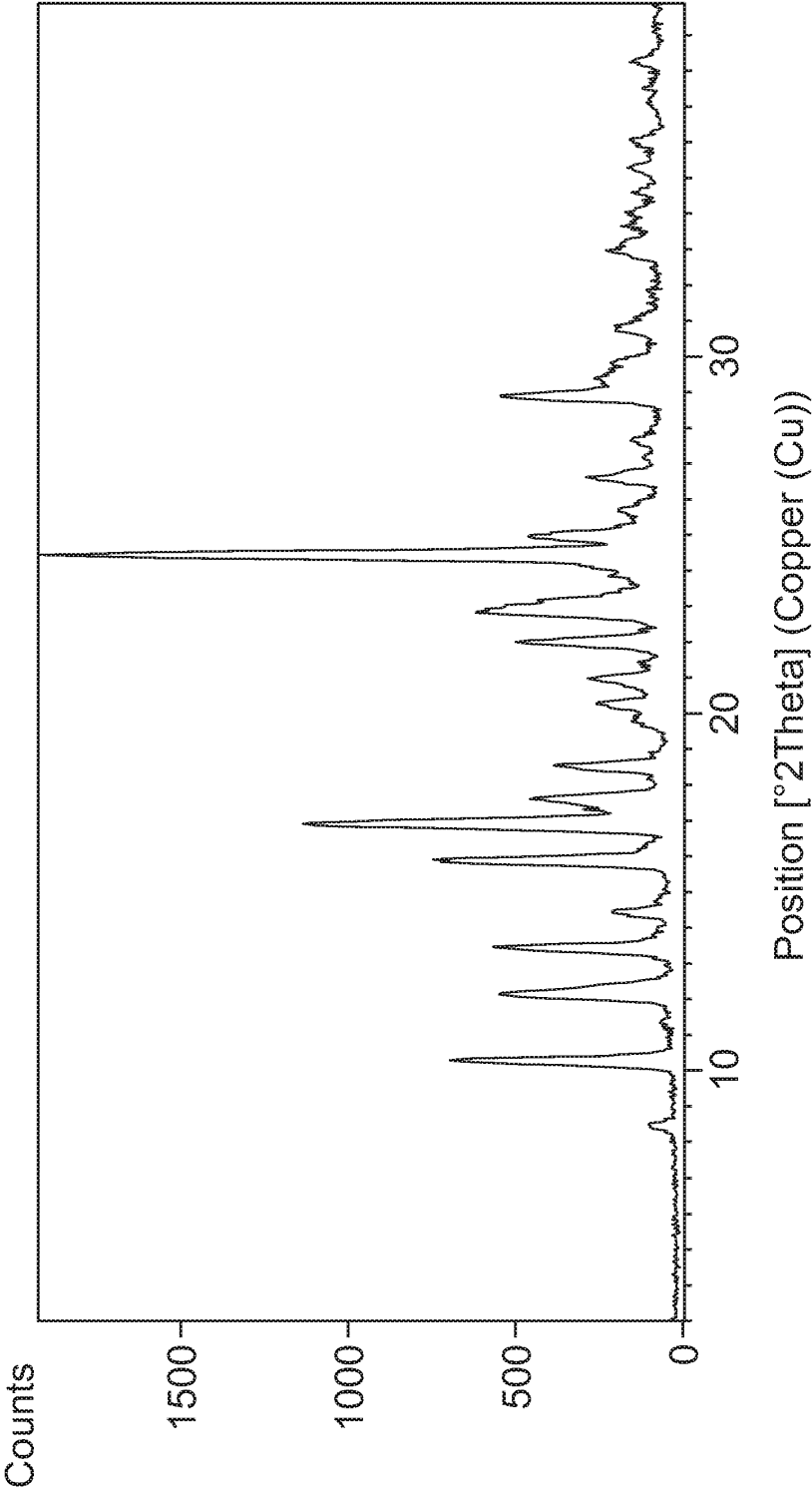


FIG. 14A

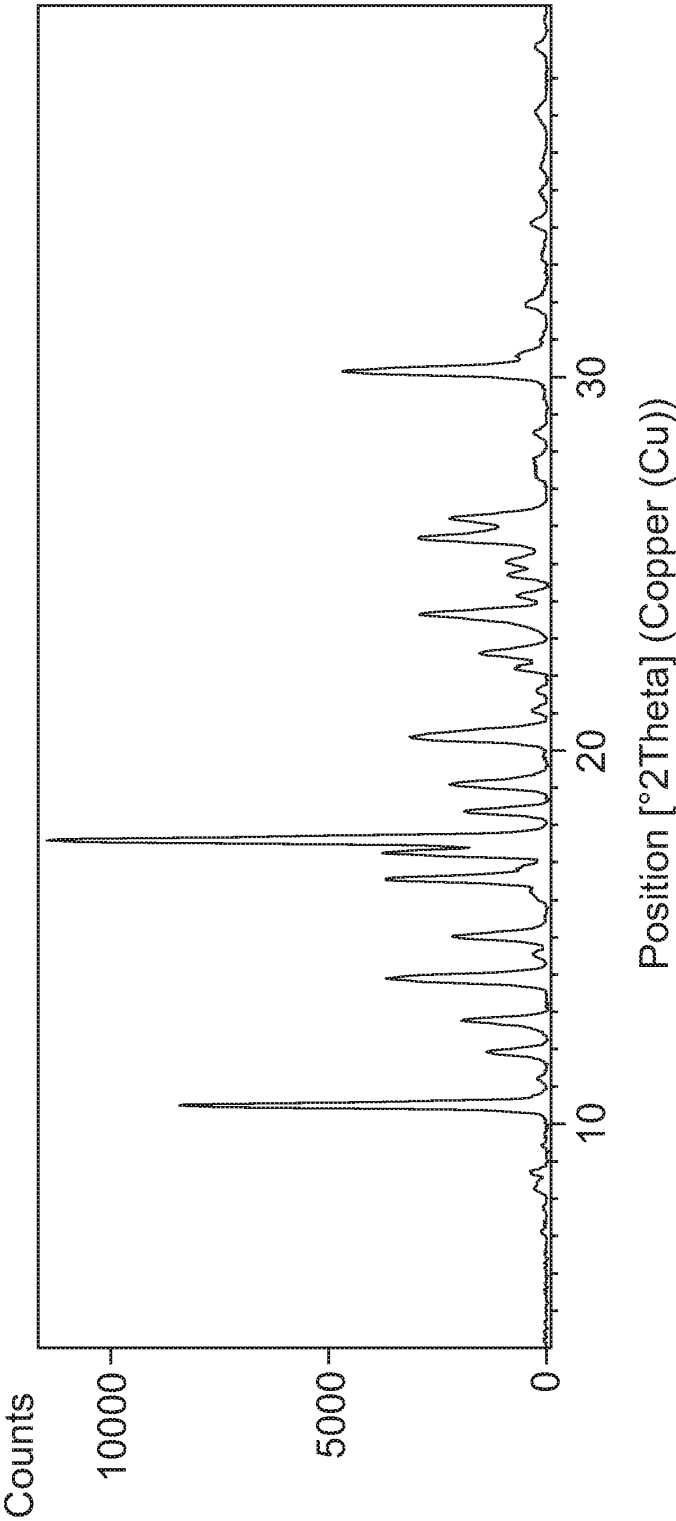


FIG. 14B

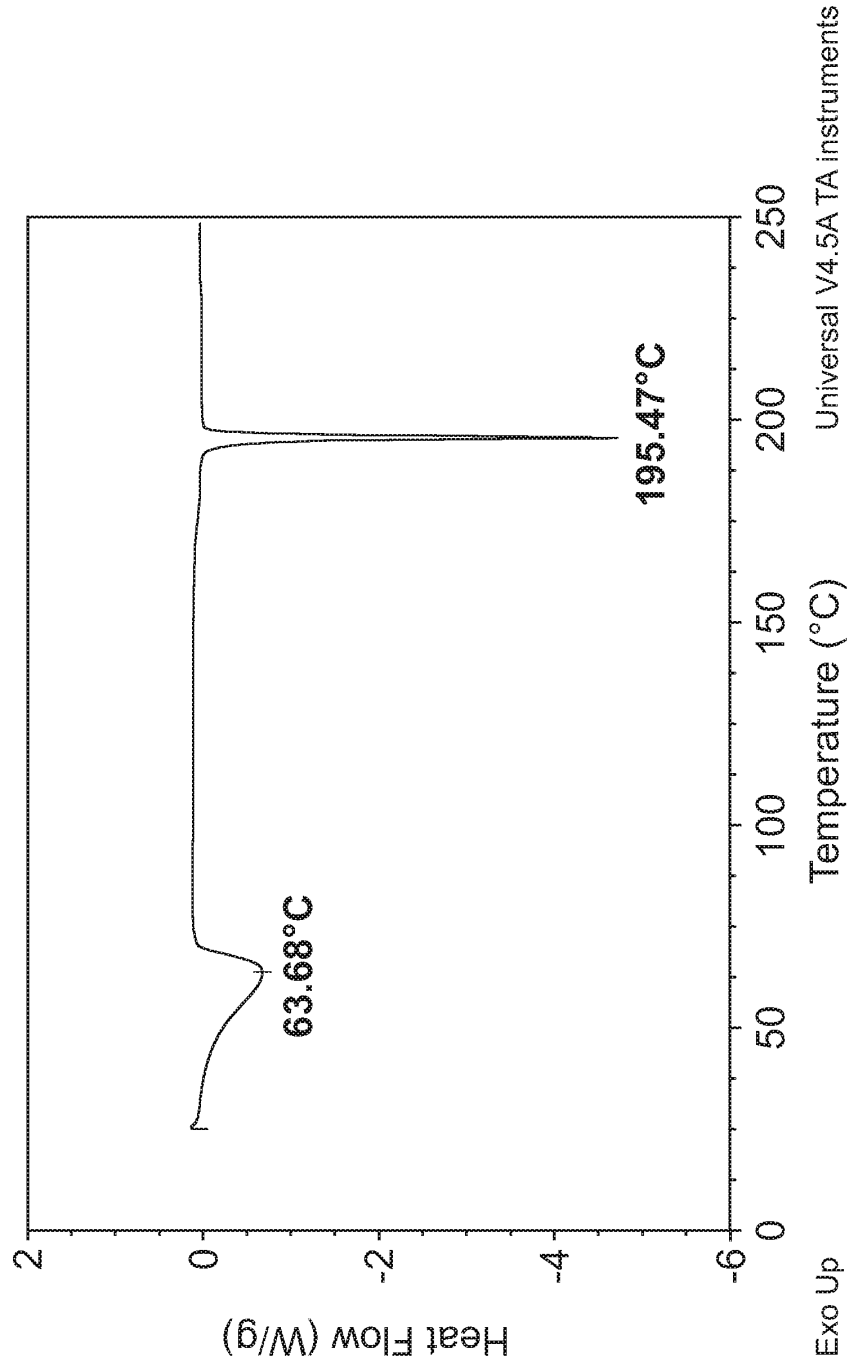


FIG. 15

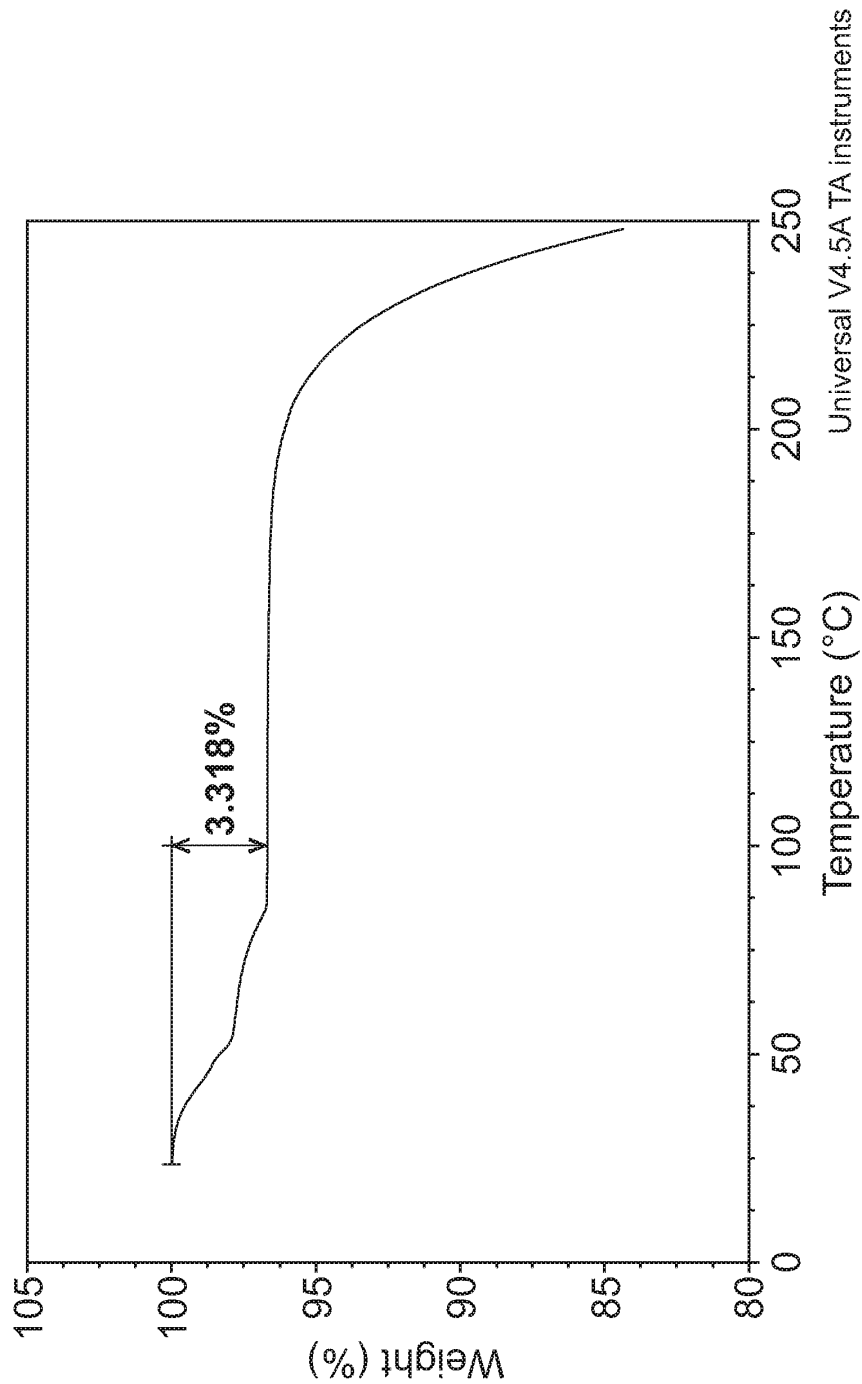


FIG. 16

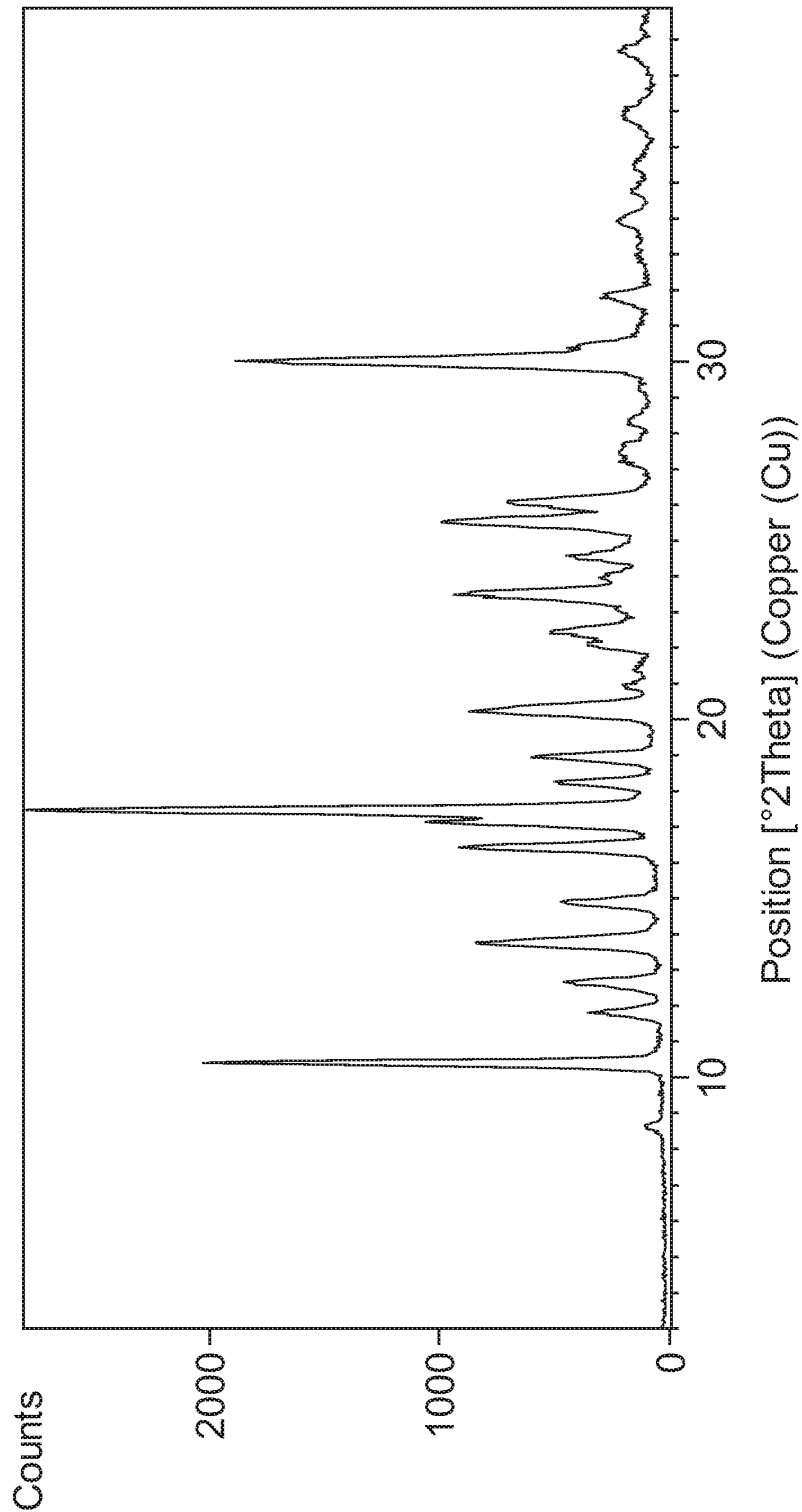


FIG. 17

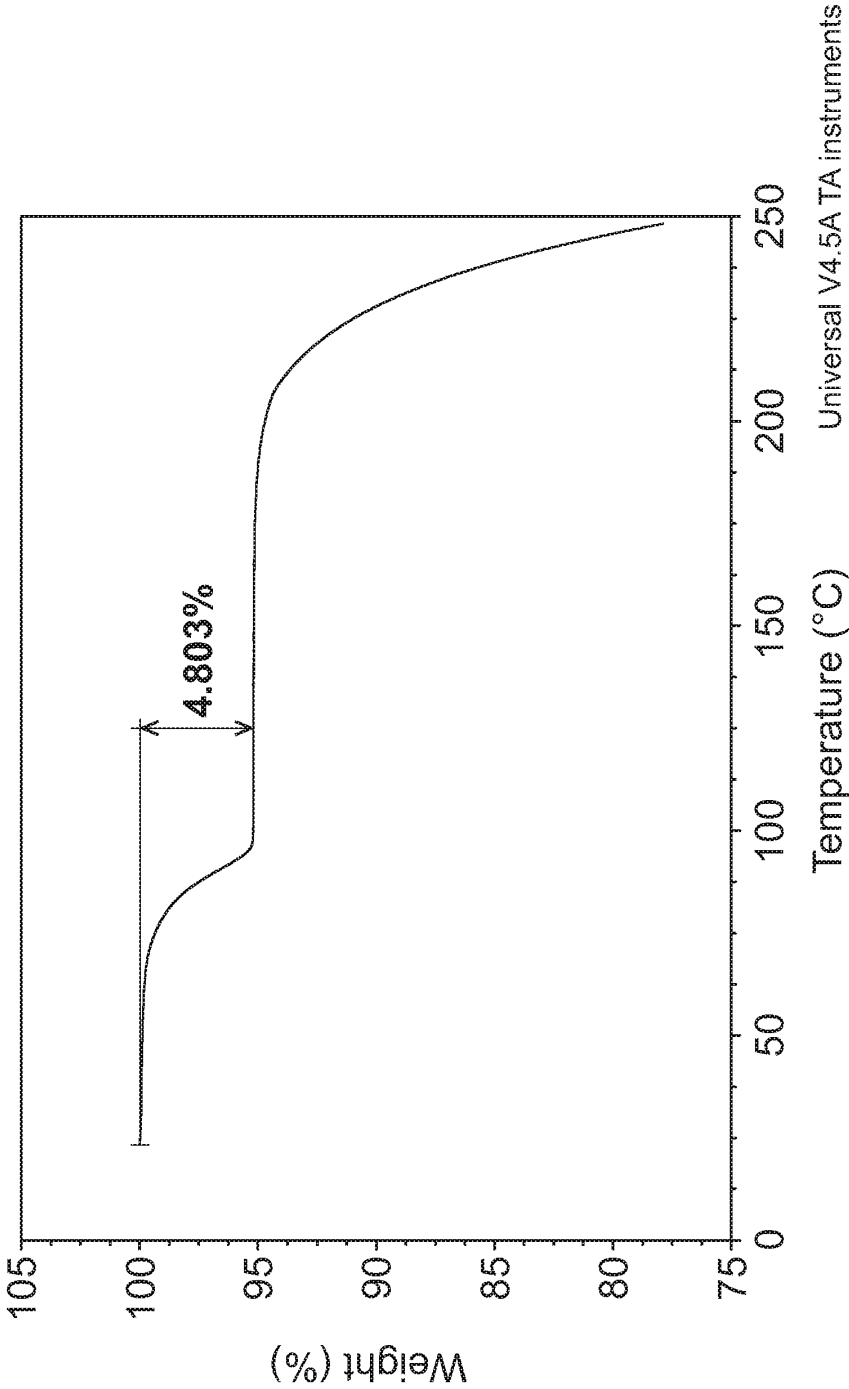


FIG. 18

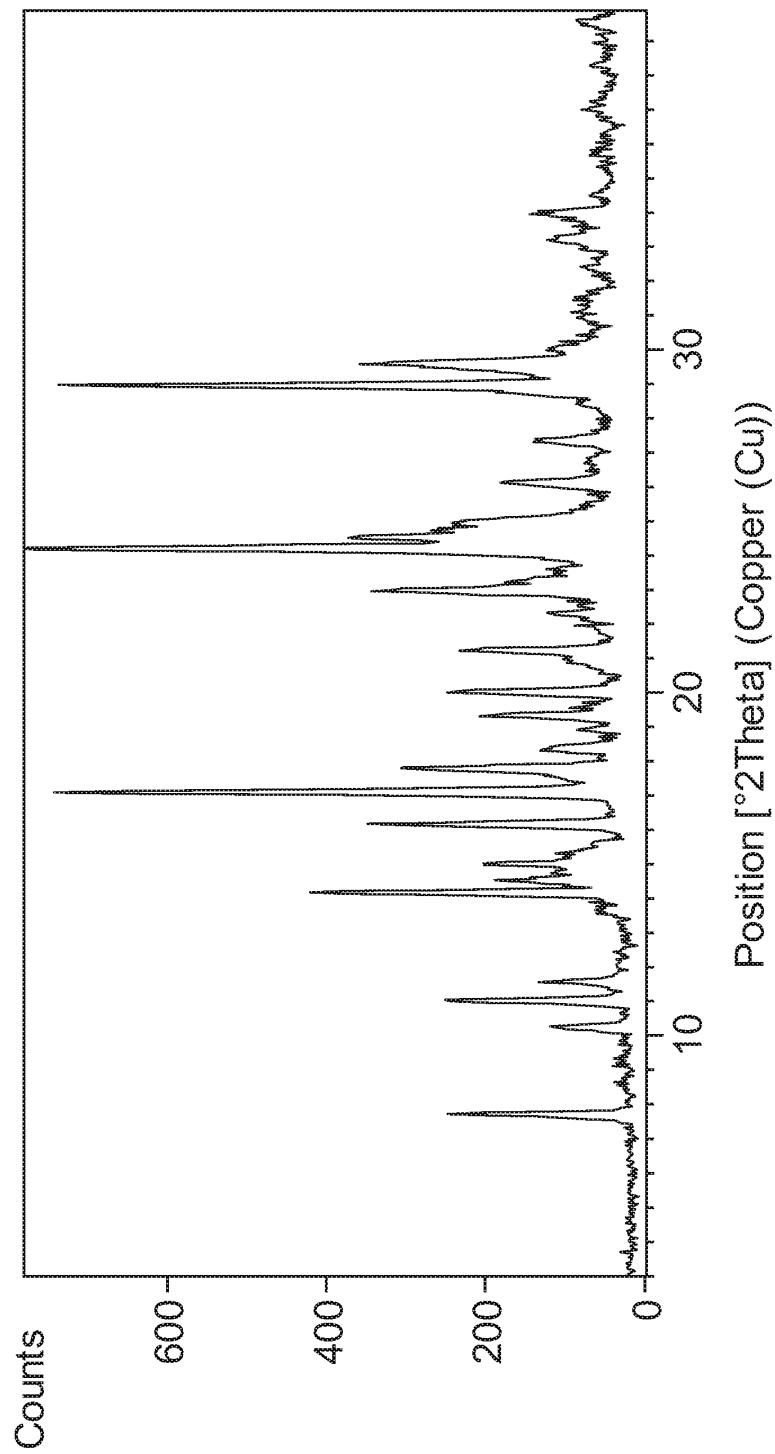


FIG. 19

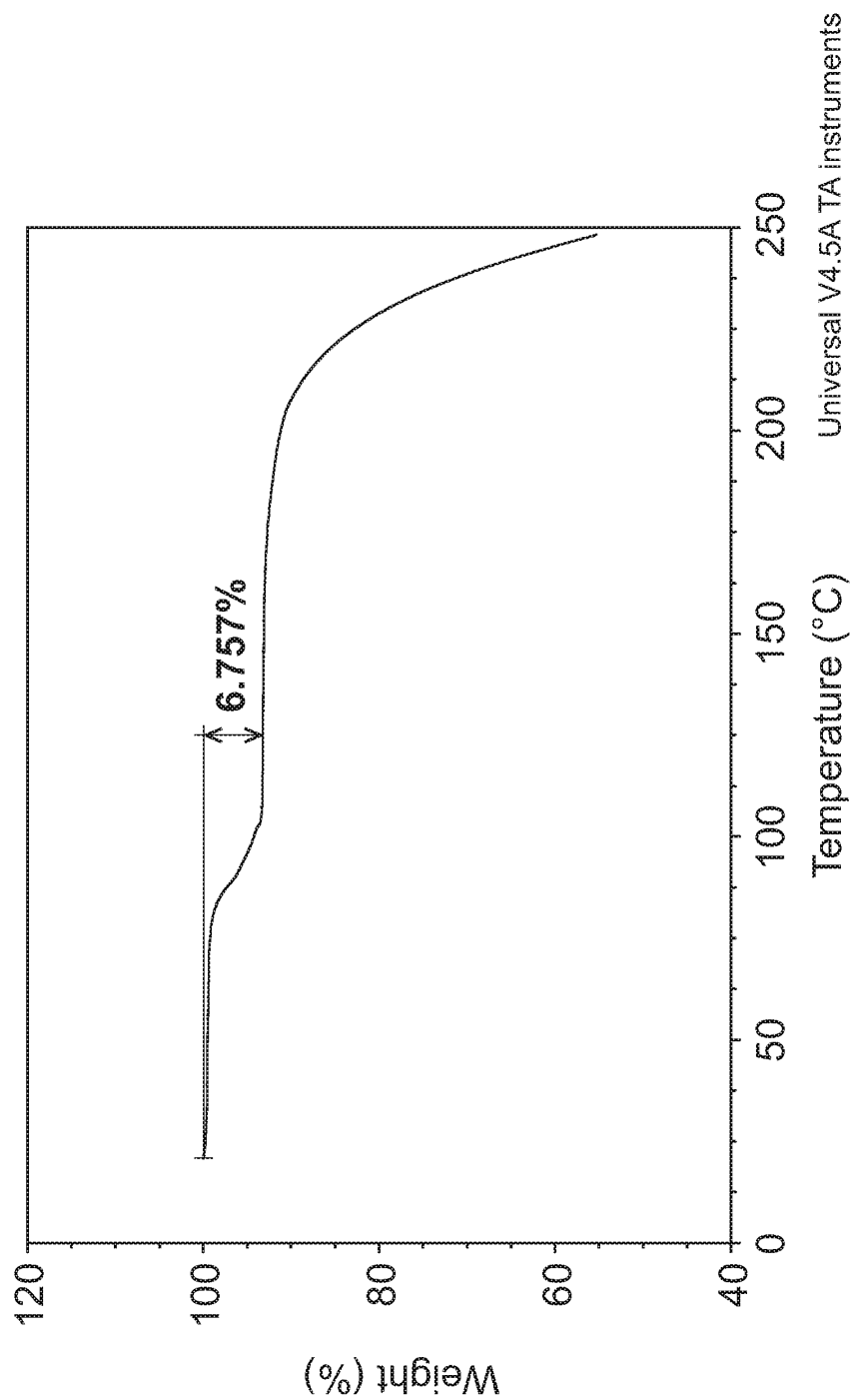


FIG. 20

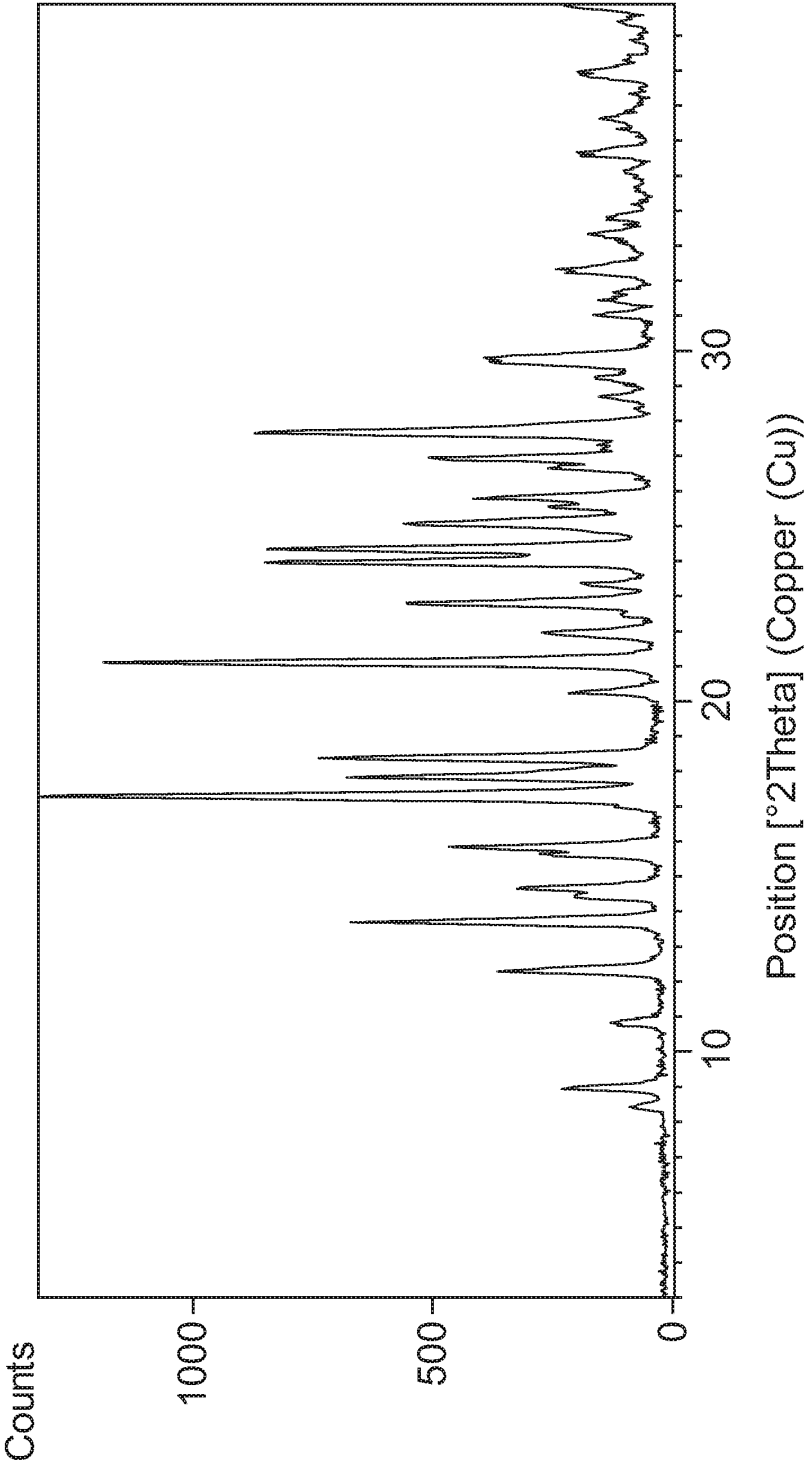


FIG. 21

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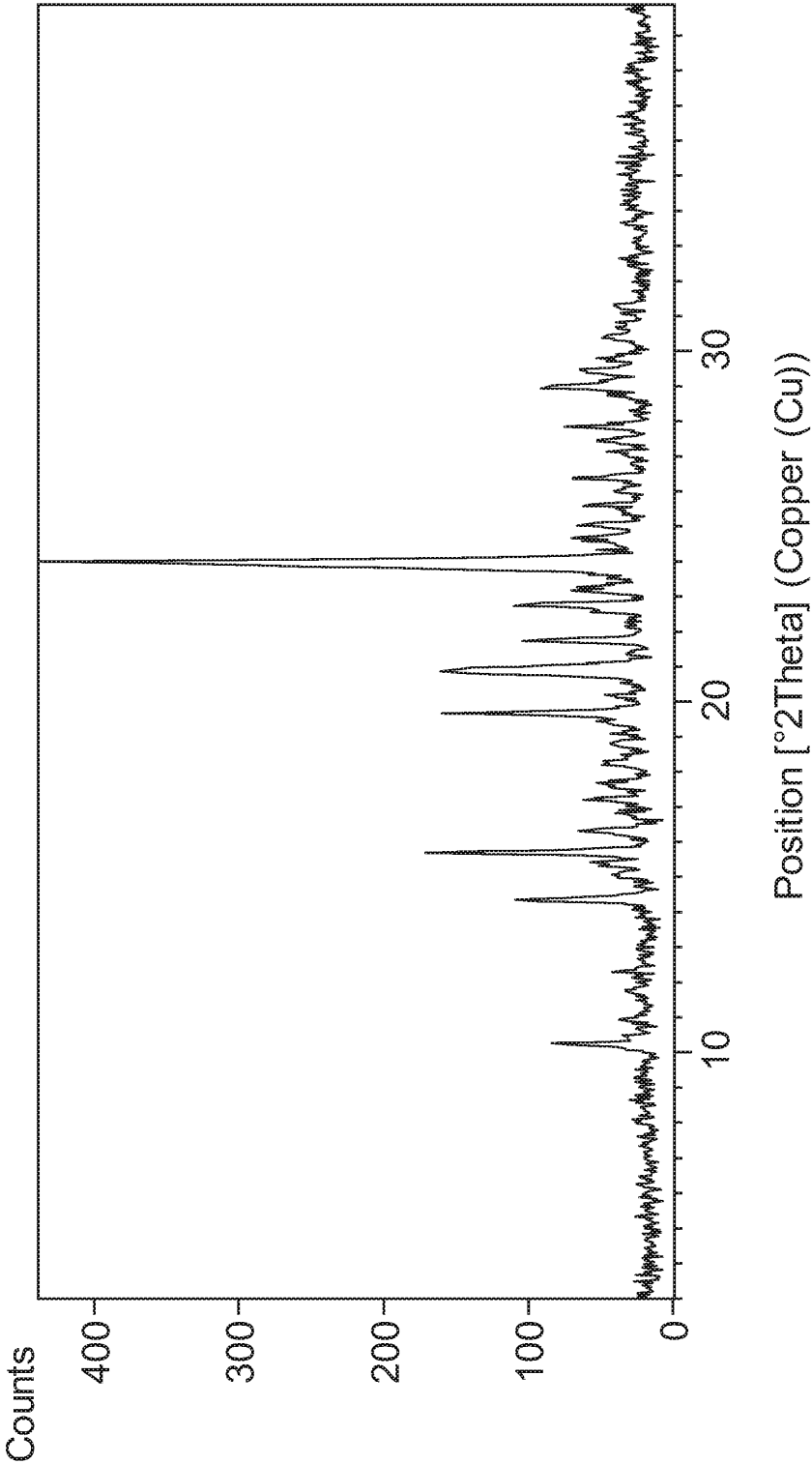


FIG. 22

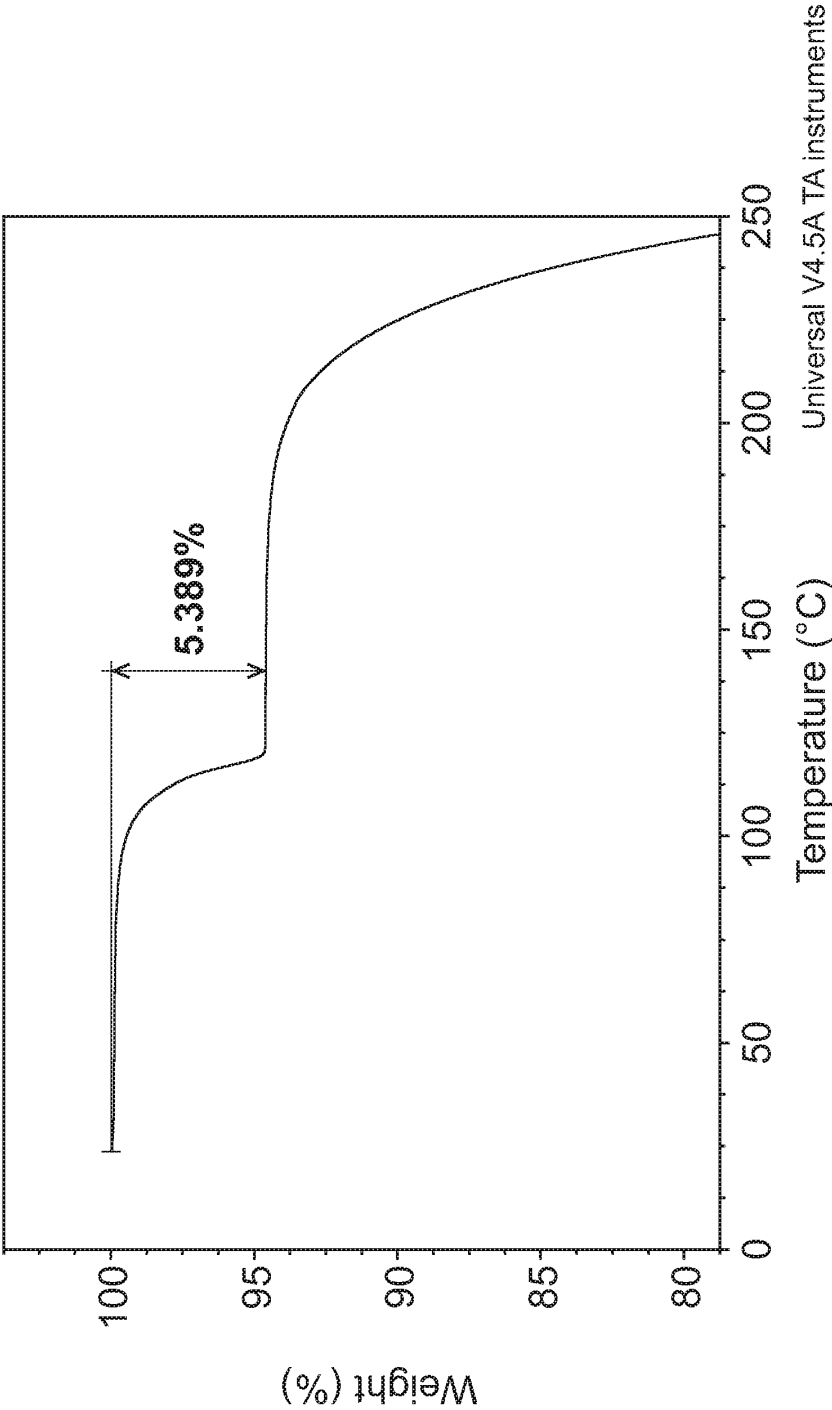


FIG. 23

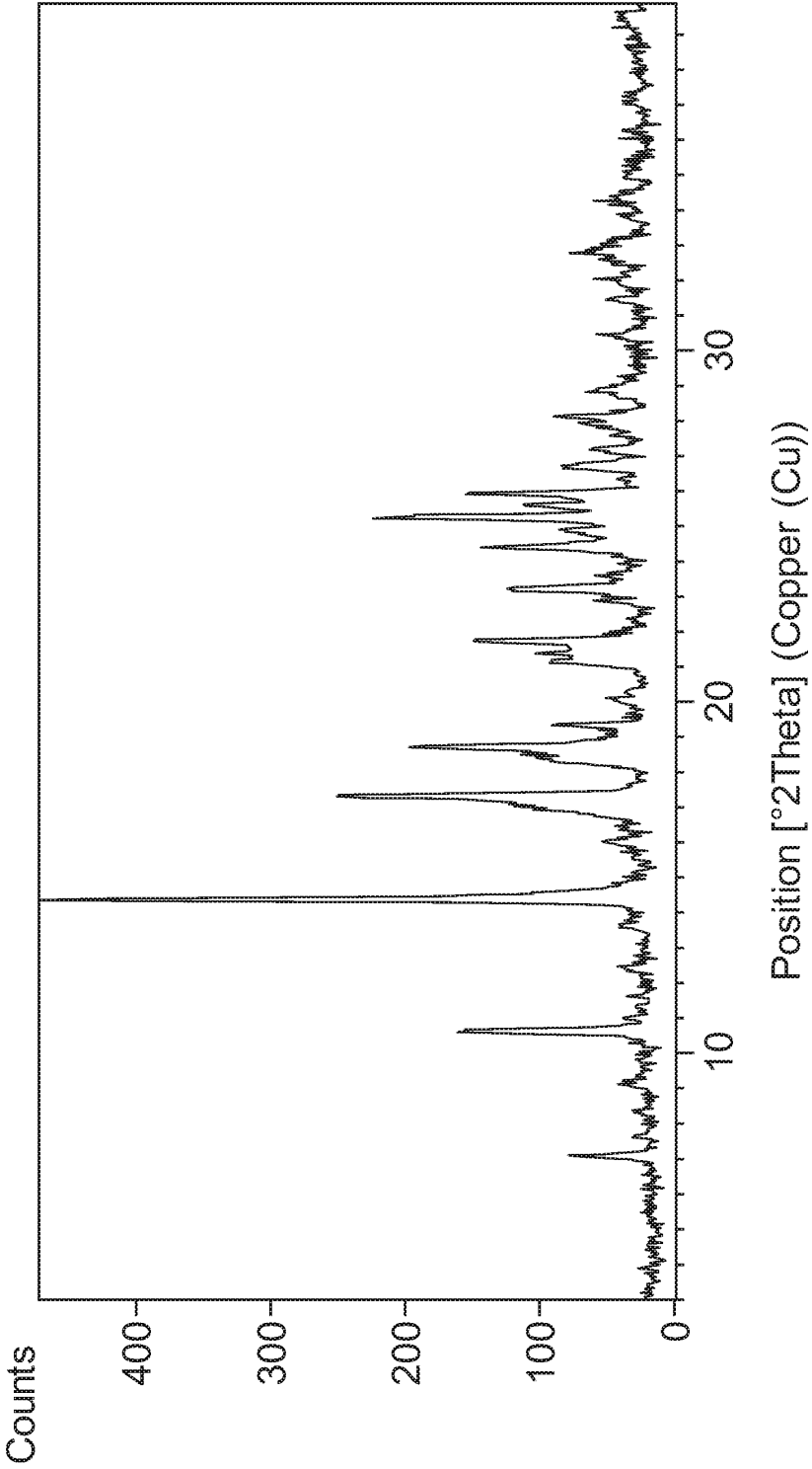


FIG. 24

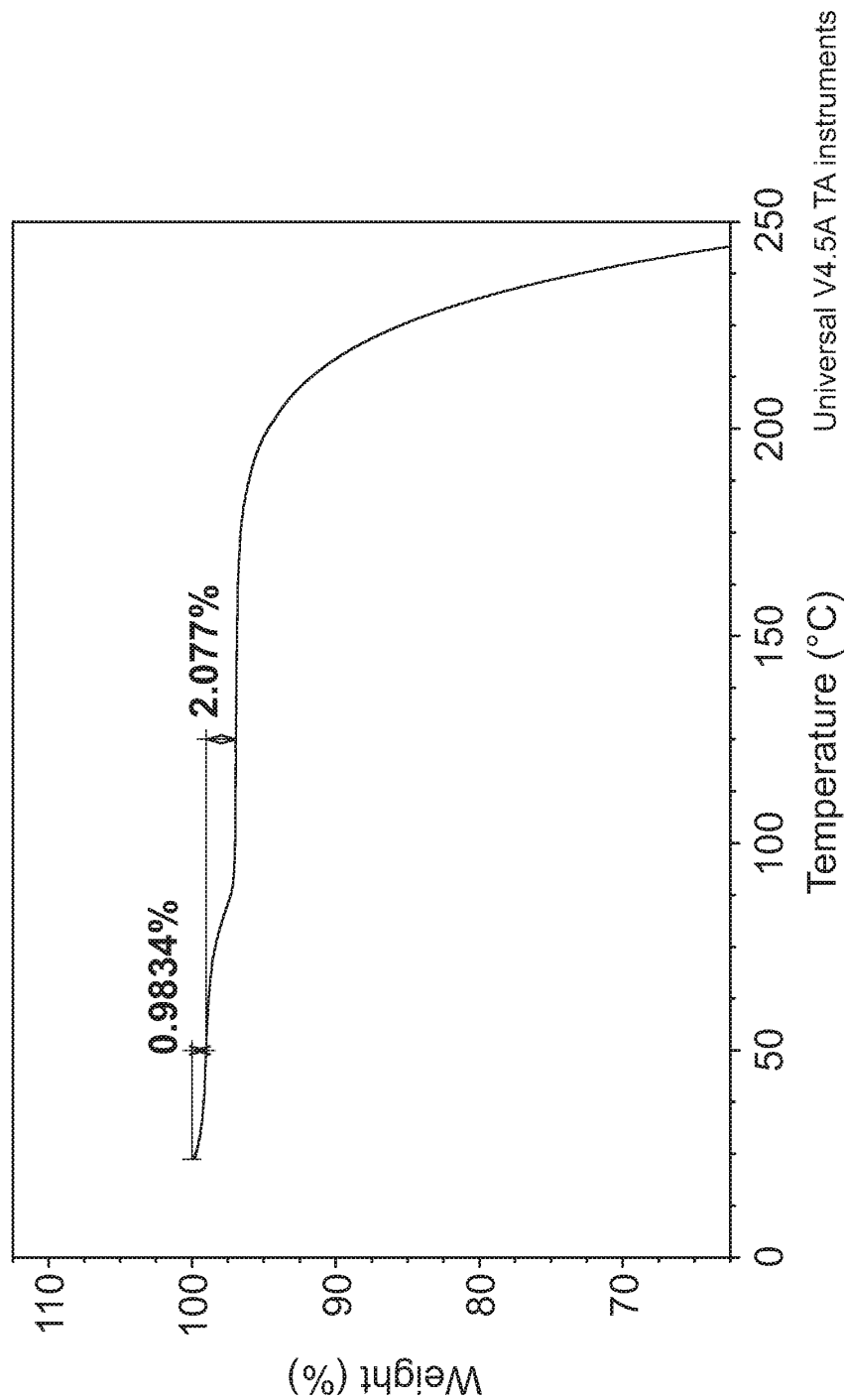


FIG. 25

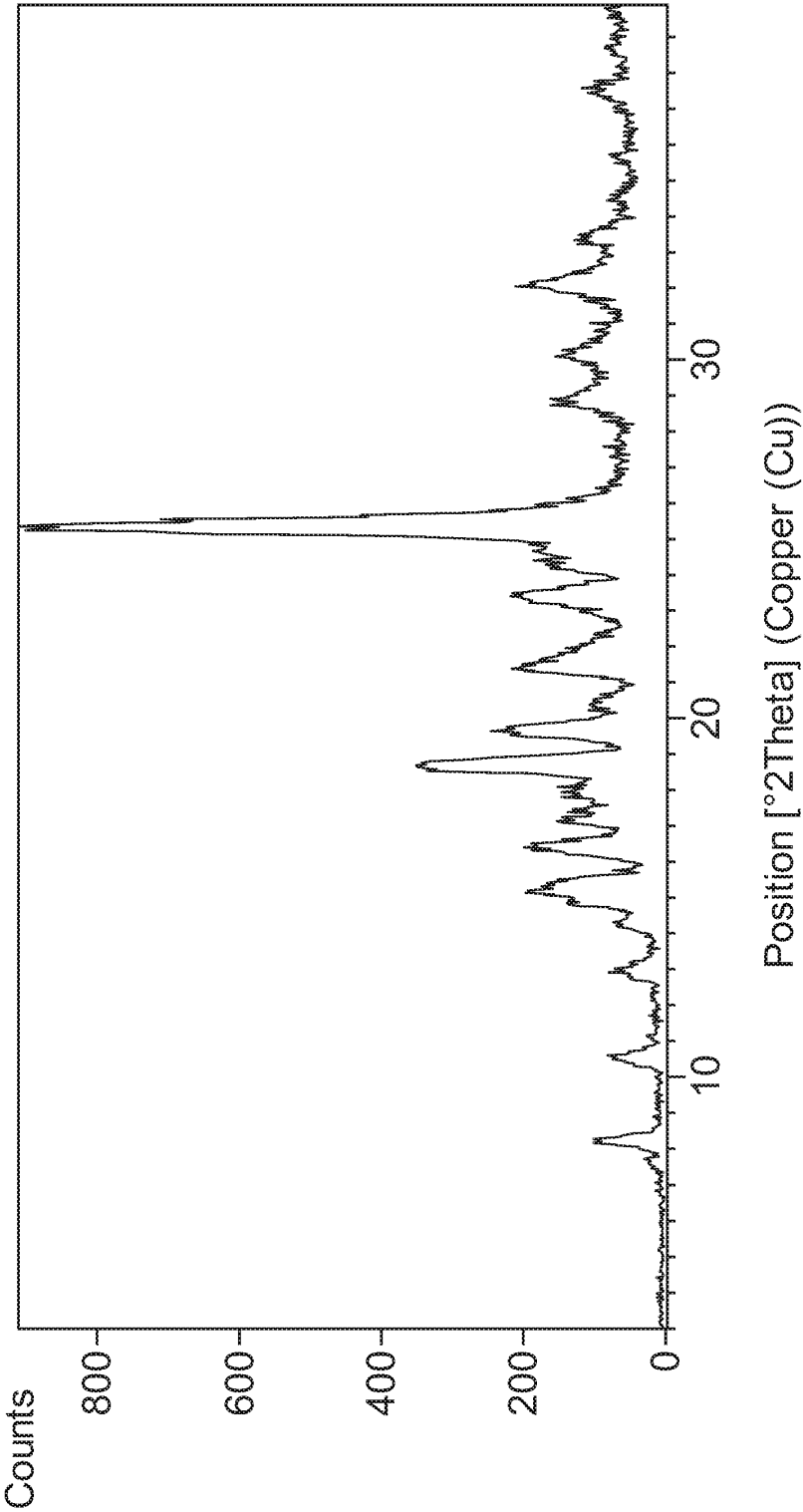


FIG. 26

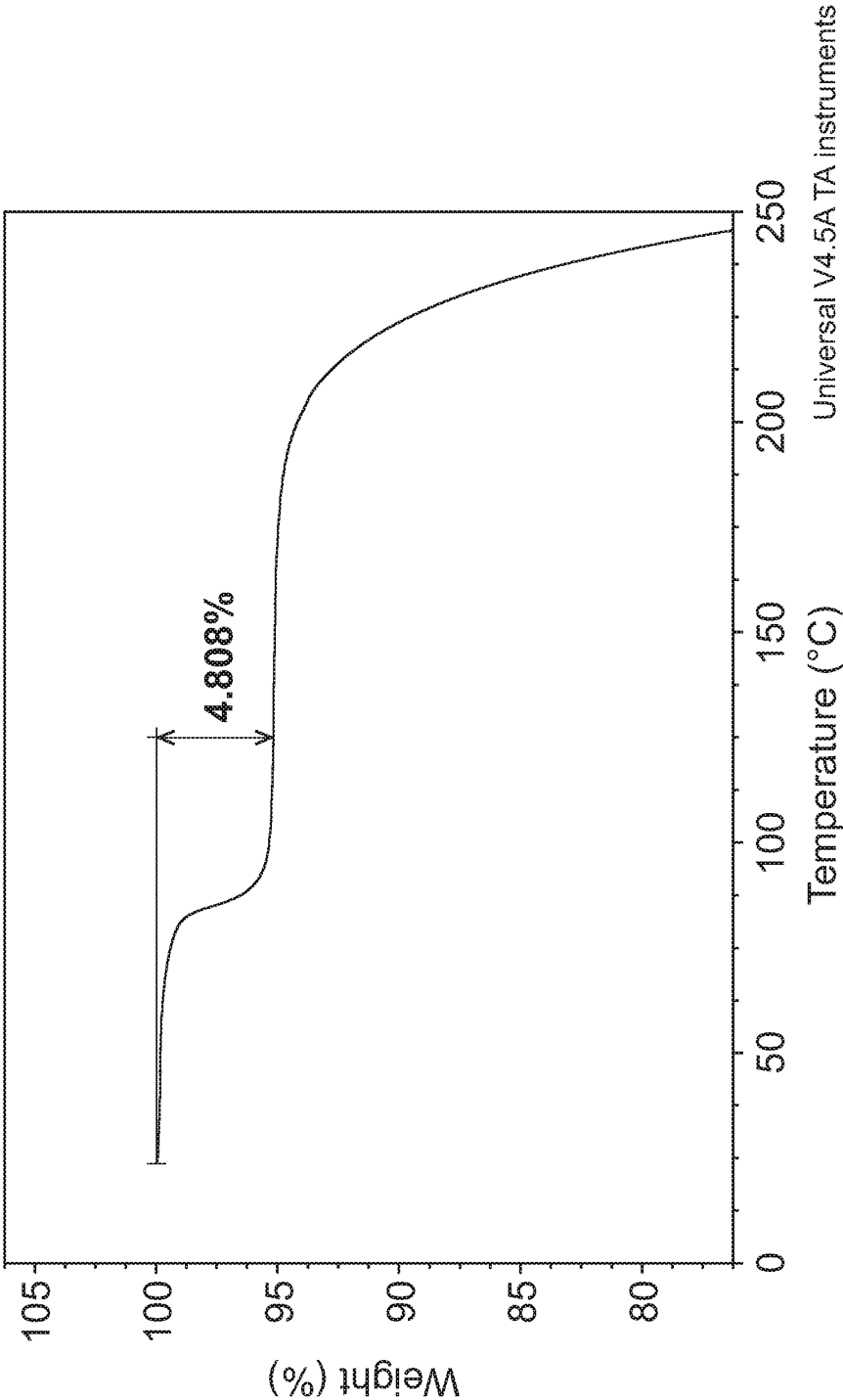


FIG. 27